

# KAE-02150

## 1920 (H) x 1080 (V) Interline CCD Image Sensor

The KAE-02150 Image Sensor is a 1080p (1920 × 1080) CCD in a 2/3" optical format that provides exceptional imaging performance in extreme low light applications. Each of the sensor's four outputs incorporate both a conventional horizontal CCD register and a high gain EMCCD register.

An intra-scene switchable gain feature samples each charge packet on a pixel-by-pixel basis. This enables the camera system to determine whether the charge will be routed through the normal gain output or the EMCCD output based on a user selectable threshold. This feature enables imaging in extreme low light, even when bright objects are within a dark scene, allowing a single camera to capture quality images from sunlight to starlight.

This image sensor is based on the 5.5-micron Interline Transfer CCD Platform, and features extended dynamic range, excellent imaging performance, and a flexible readout architecture that enables use of 1, 2, or 4 outputs. A vertical overflow drain structure suppresses image blooming, provides excellent MTF, and enables electronic shuttering for precise exposure control.

**Table 1. GENERAL SPECIFICATIONS**

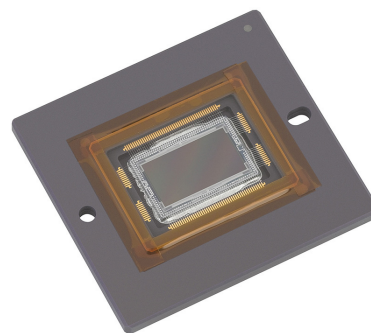
Parameter	Typical Value
Architecture	Interline CCD; with EMCCD
Total Number of Pixels	2004 (H) × 1144 (V)
Number of Effective Pixels	1960 (H) × 1120 (V)
Number of Active Pixels	1920 (H) × 1080 (V)
Pixel Size	5.5 μm (H) × 5.5 μm (V)
Active Image Size	10.56 mm (H) × 5.94 mm (V) 12.1 mm (Diag.), 2/3" Optical Format
Aspect Ratio	16:9
Number of Outputs	1, 2, or 4
Charge Capacity	20,000 e <sup>-</sup>
Output Sensitivity	44 μV/e <sup>-</sup>
Quantum Efficiency Mono / Color (RGB)	50% / 33%, 41%, 43%
Read Noise (20 MHz) Normal Mode (1× Gain) Intra-Scene Mode (20× Gain)	9 e <sup>-</sup> rms < 1 e <sup>-</sup> rms
Dark Current (0°C) Photodiode, VCCD	< 0.1 e <sup>-</sup> /s, 6 e <sup>-</sup> /s
Dynamic Range Normal Mode (1× Gain) Intra-Scene Mode (20× Gain)	68 dB 86 dB
Charge Transfer Efficiency	0.999999
Blooming Suppression	> 1000 X
Smear	-100 dB
Image Lag	< 1 e <sup>-</sup>
Maximum Pixel Clock Speed	40 MHz
Maximum Frame Rate Normal Mode, Intra-Scene Mode	60 fps (40 MHz), 30 fps (20 MHz)
Package	135 pin PGA
Cover Glass	Clear Glass, Taped

NOTE: All Parameters are specified at T = 0°C unless otherwise noted.



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**Figure 1. KAE-02150 Interline CCD  
Image Sensor**

### Features

- Intra-Scene Switchable Gain
- Wide Dynamic Range
- Low Noise Architecture
- Exceptional Low Light Imaging
- Global Shutter
- Excellent Image Uniformity and MTF
- Bayer Color Pattern and Monochrome

### Applications

- Surveillance
- Scientific Imaging
- Medical Imaging
- Intelligent Transportation

### ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

# KAE-02150

## ORDERING INFORMATION

US export controls apply to all shipments of this product designated for destinations outside of the US and Canada, requiring ON Semiconductor to obtain an export license

from the US Department of Commerce before image sensors or evaluation kits can be exported.

**Table 2. ORDERING INFORMATION**

Part Number	Description	Marking Code
KAE-02150-ABB-JP-FA	Monochrome, Microlens, PGA Package, Taped Clear Cover Glass (No Coatings), Standard Grade	KAE-02150-ABB Serial Number
KAE-02150-ABB-JP-EE	Monochrome, Microlens, PGA Package, Taped Clear Cover Glass (No Coatings), Engineering Grade	
KAE-02150-FBB-JP-FA	Color (Bayer RGB), Microlens, PGA Package, Taped Clear Cover Glass (No Coatings), Standard Grade	KAE-02150-FBB Serial Number
KAE-02150-FBB-JP-EE	Color (Bayer RGB), Microlens, PGA Package, Taped Clear Cover Glass (No Coatings), Engineering Grade	

**Table 3. EVALUATION SUPPORT**

Part Number	Description
KAE-02150-AB-A-GEVK	KAE-02150 Evaluation Kit
LENS-MOUNT-KIT-C-GEVK	Lens Mount Kit for IT-CCD Evaluation Hardware

See the ON Semiconductor *Device Nomenclature* document (TND310/D) for a full description of the naming convention used for image sensors. For reference documentation, including information on evaluation kits, please visit our web site at [www.onsemi.com](http://www.onsemi.com).

DEVICE DESCRIPTION

Architecture

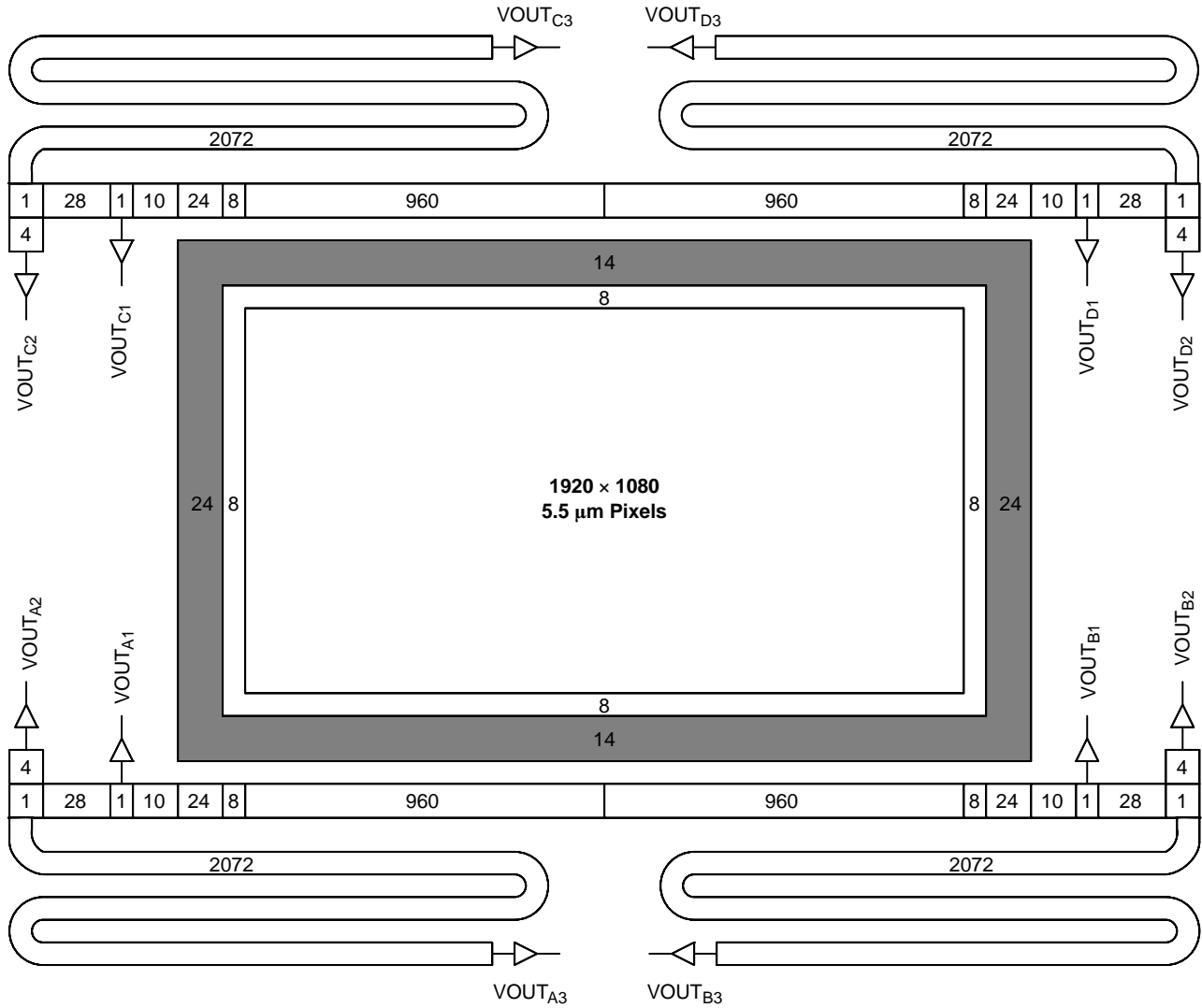


Figure 2. Block Diagram

**Dark Reference Pixels**

There are 14 dark reference rows at the top and bottom of the image sensor, as well as 24 dark reference columns on the left and right sides. However, the rows and columns at the very edges should not be included in acquiring a dark reference signal, since they may be subject to some light leakage.

**Active Buffer Pixels**

8 unshielded pixels adjacent to any leading or trailing dark reference regions are classified as active buffer pixels. These pixels are light sensitive but are not tested for defects and non-uniformities.

**Image Acquisition**

An electronic representation of an image is formed when incident photons falling on the sensor plane create

electron-hole pairs within the individual silicon photodiodes. These photoelectrons are collected locally by the formation of potential wells at each photo-site. Below photodiode saturation, the number of photoelectrons collected at each pixel is linearly dependent upon light level and exposure time and non-linearly dependent on wavelength. When the photodiodes charge capacity is reached, excess electrons are discharged into the substrate to prevent blooming

**ESD Protection**

Adherence to the power-up and power-down sequence is critical. Failure to follow the proper power-up and power-down sequences may cause damage to the sensor. See Power-Up and Power-Down Sequence section.

Bayer Color Filter Pattern

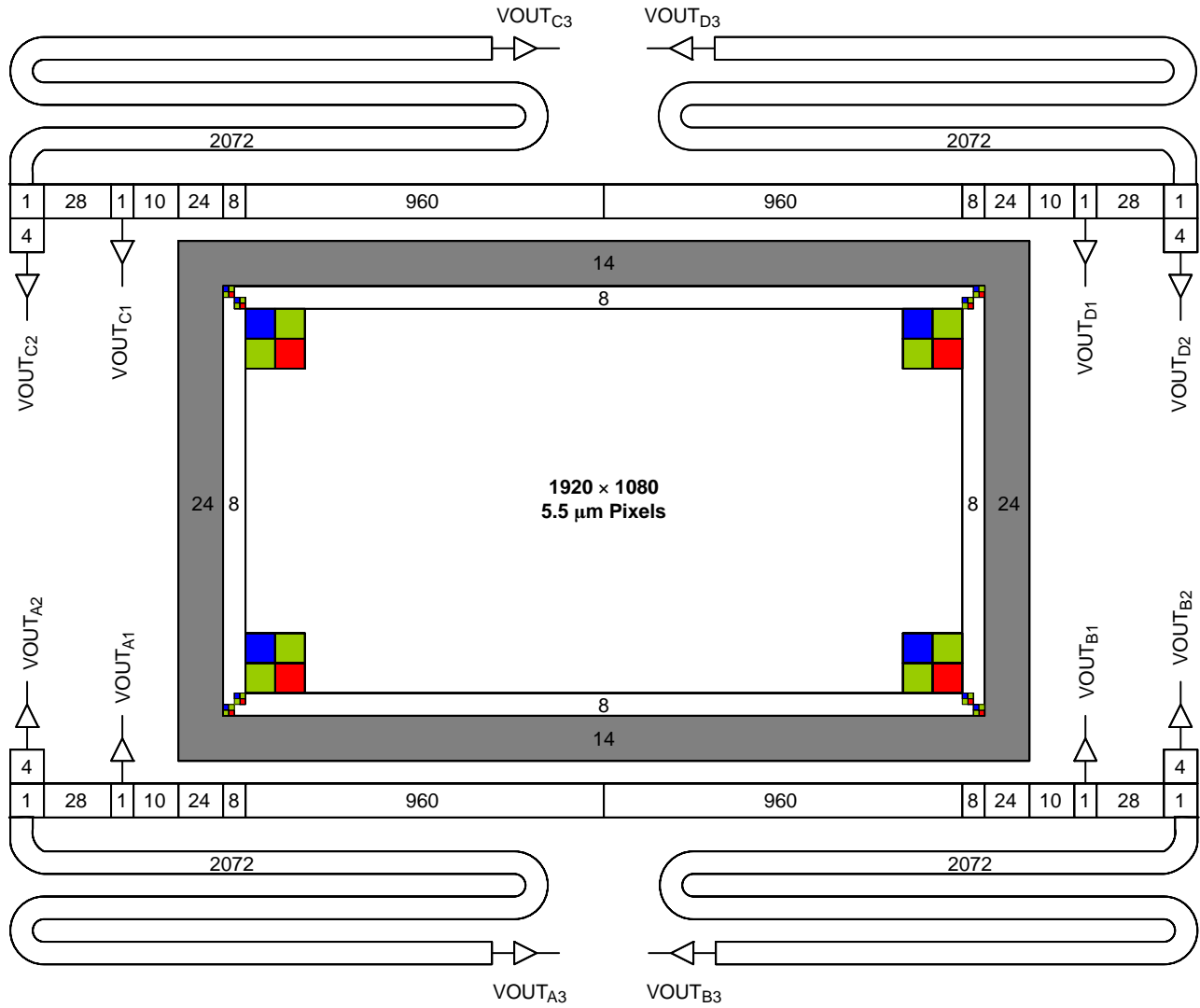


Figure 3. Bayer Color Filter Pattern

Physical Description

Pin Grid Array and Pin Description

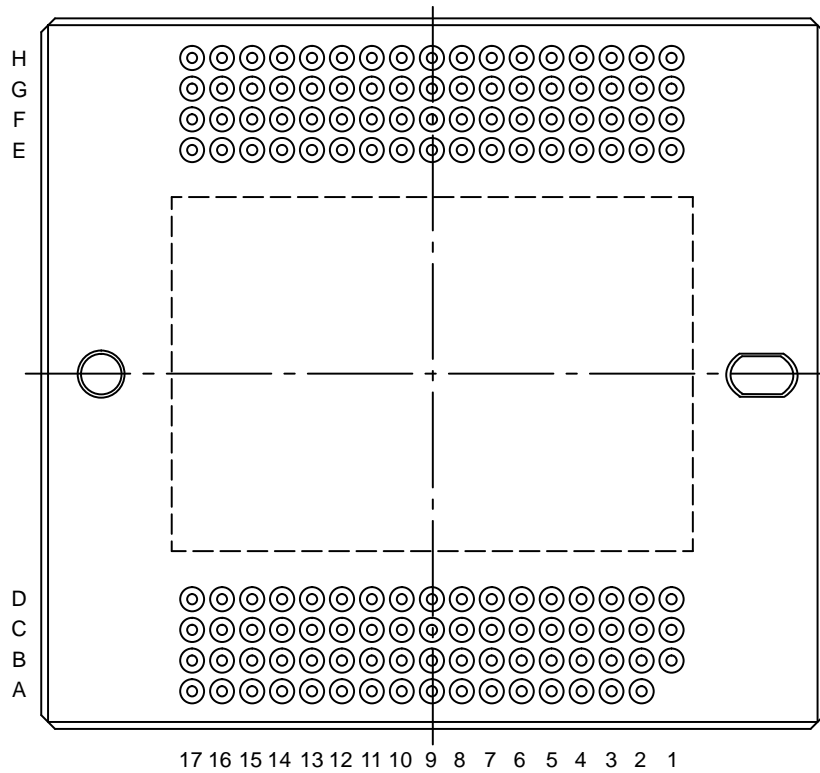


Figure 4. PGA Package Designations (Bottom View)

Table 4. PIN DESCRIPTION

Pin	Label	Description
A02	V3B	VCCD Bottom Phase 3
A03	N/C	No Connection
A04	RG2a	Amplifier 2 Reset, Quadrant A
A05	N/C	No Connection
A06	VDD23ab	Amplifier 2 and 3 Supply, Quadrants A, B
A07	H1BEMa	EMCCD Barrier Phase 1, Quadrant A
A08	H2Ba	HCCD Barrier Phase 2, Quadrant A
A09	GND	Ground
A10	H2Bb	HCCD Barrier Phase 2, Quadrant B
A11	H1BEMb	EMCCD barrier phase 1, Quadrant B
A12	VDD23ab	Amplifier 2 and 3 Supply, Quadrants A, B
A13	N/C	No Connection
A14	RG2a	Amplifier 2 Reset, Quadrant B
A15	N/C	No Connection
A16	V3B	VCCD Bottom Phase 3
A17	ESD	ESD Protection Disable
B01	DEVID	Device ID Resistor
B02	V4B	VCCD Bottom Phase 4
B03	VOOUT1a	Amplifier 1 Output, Quadrant A

**Table 4. PIN DESCRIPTION** (continued)

Pin	Label	Description
B04	VOOUT2a	Video Output 2, Quadrant A
B05	H2SW3a	HCCD Output 3 Selector, Quadrant A
B06	VOOUT3a	Video Output 3, Quadrant A
B07	H2BEMa	EMCCD Barrier Phase 2, Quadrant A
B08	H1Ba	HCCD Barrier Phase 1, Quadrant A
B09	GND	Ground
B10	H1Bb	HCCD Barrier Phase 1, Quadrant B
B11	H2BEMb	EMCCD Barrier Phase 2, Quadrant B
B12	VOOUT3b	Video Output 3, Quadrant B
B13	H2SW3b	HCCD Output 3 Selector, Quadrant B
B14	VOOUT2b	Video Output 2, Quadrant B
B15	VOOUT1b	Amplifier 1 Output, Quadrant B
B16	V4B	VCCD Bottom Phase 4
B17	SUB	Substrate
C01	V1B	VCCD Bottom Phase 1
C02	N/C	No Connection
C03	VSS1a	Amplifier 1 Return, Quadrant A
C04	VDD23ab	Amplifier 2 and 3 Supply, Quadrants A, B
C05	H2SW2a	HCCD Output 2 Selector, Quadrant A
C06	N/C	No Connection
C07	H1SEMa	EMCCD Storage Multiplier Phase 1, Quadrant A
C08	H2Sa	HCCD Storage Phase 2, Quadrant A
C09	GND	Ground
C10	H2Sb	HCCD Storage Phase 2, Quadrant B
C11	H1SEMb	EMCCD Storage Multiplier Phase 1, Quadrant B
C12	N/C	No Connection
C13	H2SW2b	HCCD Output 2 Selector, Quadrant B
C14	VDD23ab	Amplifier 2 and 3 Supply, Quadrants A, B
C15	VSS1b	Amplifier 1 Return, Quadrant B
C16	N/C	No Connection
C17	V1B	VCCD Bottom Phase 1
D01	V2B	VCCD Bottom Phase 2
D02	VDD1a	Amplifier 1 Supply, Quadrant A
D03	RG1a	Amplifier 1 Reset, Quadrant A
D04	H2Xa	Floating Gate Exit HCCD Gate, Quadrant A
D05	H2La	HCCD Last Gate, Outputs 1, 2 and 3, Quadrant A
D06	RG3a	Amplifier 3 Reset, Quadrant A
D07	H2SEMa	EMCCD Storage Multiplier Phase 2, Quadrant A
D08	H1Sa	HCCD Storage Phase 1, Quadrant A
D09	GND	Ground
D10	H1Sb	HCCD Storage Phase 1, Quadrant B
D11	H2SEMb	EMCCD Storage Multiplier Phase 2, Quadrant B
D12	RG3b	Amplifier 3 Reset, Quadrant B
D13	H2Lb	HCCD Last Gate, Outputs 1, 2 and 3, Quadrant B
D14	H2Xb	Floating Gate Exit HCCD Gate, Quadrant B

**Table 4. PIN DESCRIPTION** (continued)

Pin	Label	Description
D15	RG1b	Amplifier 1 Reset, Quadrant B
D16	VDD1b	Amplifier 1 Supply, Quadrant B
D17	V2B	VCCD Bottom Phase 2
E01	V2T	VCCD Top Phase 2
E02	VDD1c	Amplifier 1 Supply, Quadrant C
E03	RG1c	Amplifier 1 Reset, Quadrant C
E04	H2Xc	Floating Gate Exit HCCD Gate, Quadrant C
E05	H2Lc	HCCD Last Gate, Outputs 1, 2 and 3, Quadrant C
E06	RG3c	Amplifier 3 Reset, Quadrant C
E07	H2SEMc	EMCCD Storage Multiplier Phase 2, Quadrant C
E08	H1Sc	HCCD Storage Phase 1, Quadrant C
E09	GND	Ground
E10	H1Sd	HCCD Storage Phase 1, Quadrant D
E11	H2SEMd	EMCCD Storage Multiplier Phase 2, Quadrant D
E12	RG3d	Amplifier 3 Reset, Quadrant D
E13	H2Ld	HCCD Last Gate, Outputs 1, 2 and 3, Quadrant D
E14	H2Xd	Floating Gate Exit HCCD Gate, Quadrant D
E15	RG1d	Amplifier 1 Reset, Quadrant D
E16	VDD1d	Amplifier 1 Supply, Quadrant D
E17	V2T	VCCD Top Phase 2
F01	V1T	VCCD Top Phase 1
F02	N/C	No Connection
F03	VSS1c	Amplifier 1 Return, Quadrant C
F04	VDD23cd	Amplifier 2 and 3 Supply, Quadrants C, D
F05	H2SW2c	HCCD Output 2 Selector, Quadrant C
F06	N/C	No Connection
F07	H1SEMc	EMCCD Storage Multiplier Phase 1, Quadrant C
F08	H2Sc	HCCD Storage Phase 2, Quadrant C
F09	GND	Ground
F10	H2Sd	HCCD Storage Phase 2, Quadrant D
F11	H1SEMd	EMCCD Storage Multiplier Phase 1, Quadrant D
F12	N/C	No Connection
F13	H2SW2d	HCCD Output 2 Selector, Quadrant D
F14	VDD23cd	Amplifier 2 and 3 Supply, Quadrants C, D
F15	VSS1d	Amplifier 1 Return, Quadrant D
F16	N/C	No Connection
F17	V1T	VCCD Top Phase 1
G01	ESD	ESD Protection Disable
G02	V4T	VCCD Top Phase 4
G03	VOU1c	Amplifier 1 Output, Quadrant C
G04	VOU2c	Video Output 2, Quadrant C
G05	H2SW3c	HCCD Output 3 Selector, Quadrant C
G06	VOU3c	Video Output 3, Quadrant C
G07	H2BEMc	EMCCD Barrier Phase 2, Quadrant C
G08	H1Bc	HCCD Barrier Phase 1, Quadrant C

**Table 4. PIN DESCRIPTION** (continued)

Pin	Label	Description
G09	GND	Ground
G10	H1Bd	HCCD Barrier Phase 1, Quadrant D
G11	H2BEMd	EMCCD Barrier Phase 2, Quadrant D
G12	VOUT3d	Video Output 3, Quadrant D
G13	H2SW3d	HCCD Output 3 Selector, Quadrant D
G14	VOUT2d	Video Output 2, Quadrant D
G15	VOUT1d	Amplifier 1 Output, Quadrant D
G16	V4T	VCCD Top Phase 4
G17	SUB	Substrate
H01	TD	Temperature Diode Sensor
H02	V3T	VCCD Top Phase 3
H03	N/C	No Connection
H04	RG2c	Amplifier 2 Reset, Quadrant C
H05	N/C	No Connection
H06	VDD23cd	Amplifier 2 and 3 Supply, Quadrants C, D
H07	H1BEMc	EMCCD Barrier Phase 1, Quadrant C
H08	H2Bc	HCCD Barrier Phase 2, Quadrant C
H09	GND	Ground
H10	H2Bd	HCCD Barrier Phase 2, Quadrant D
H11	H1BEMd	EMCCD Barrier Phase 1, Quadrant D
H12	VDD23cd	Amplifier 2 and 3 Supply, Quadrants C, D
H13	N/C	No Connection
H14	RG2d	Amplifier 2 Reset, Quadrant D
H15	N/C	No Connection
H16	V3T	VCCD Top Phase 3
H17	SUBREF	Substrate Voltage Reference



## IMAGING PERFORMANCE

**Table 5. TYPICAL OPERATIONAL CONDITIONS**

(Unless otherwise noted, the Imaging Performance Specifications are measured using the following conditions.)

Description	Condition	Notes
Light Source	Continuous Red, Green and Blue LED Illumination	1
Operation	Nominal Operating Voltages and Timing	
Temperature	0°C	

1. For monochrome sensor, only green LED used.

**Table 6. SPECIFICATIONS**

Description	Symbol	Min.	Nom.	Max.	Units	Sampling Plan	Temperature Tested at (°C)	Notes
Dark Field Global Non-Uniformity	DSNU	–	–	2.0	mV pp	Die	TBD	
Bright Field Global Non-Uniformity		–	2.0	5.0	% rms	Die	TBD	1
Bright Field Global Peak to Peak Non-Uniformity	PRNU	–	5.0	15.0	% pp	Die	TBD	1
Bright Field Center Non-Uniformity		–	1.0	2.0	% rms	Die	TBD	1
Maximum Photoresponse Nonlinearity (EMCCD Gain = 1)	NL	–	2	–	%	Design		2
Maximum Gain Difference Between Outputs (EMCCD Gain = 1)	$\Delta G$	–	10	–	%	Design		2
Maximum Signal Error due to Nonlinearity Differences (EMCCD Gain = 1)	$\Delta NL$	–	1	–	%	Design		2
Horizontal CCD Charge Capacity	$H_{Ne}$	–	30	–	$ke^-$	Design		
Vertical CCD Charge Capacity	$V_{Ne}$	–	30	–	$ke^-$	Design		
Photodiode Charge Capacity	$P_{Ne}$	–	20	–	$ke^-$	Die	TBD	3
Horizontal CCD Charge Transfer Efficiency	HCTE	0.999995	0.999999	–		Die		
Vertical CCD Charge Transfer Efficiency	VCTE	0.999995	0.999999	–		Die		
Photodiode Dark Current (Average)	$I_{pD}$	–	0.1	70	$e^-/p/s$	Die	0	
Vertical CCD Dark Current		–	6	–		TBD	0	
Image Lag	Lag	–	–	< 1	$e^-$	Design		
Antiblooming Factor	$X_{AB}$	1,000	–	–		Design		
Vertical Smear (blue light)	Smr	–	–100	–	dB	Design		
Read Noise (EMCCD Gain = 1)	$n_{e^-T}$	–	9	–	$e^-$ rms	Design		4
Read Noise (EMCCD Gain = 20)		–	< 1	–	$e^-$ rms			
EMCCD Excess Noise Factor (Gain = 20x)		–	1.4	–		Design	0	

Table 6. SPECIFICATIONS (continued)

Description	Symbol	Min.	Nom.	Max.	Units	Sampling Plan	Temperature Tested at (°C)	Notes
Dynamic Range (ECCD Gain = 1)	DR	–	68	–	dB	Design		4, 5
Dynamic Range (High Gain)		–	60	–	dB			
Dynamic Range (Intra-Scene)		–	86	–	dB			
Output Amplifier DC Offset (VOUT2, VOUT3)	V <sub>ODC</sub>	8.0	10	12.0	V	Die	TBD	
Output Amplifier DC Offset (VOUT1)	V <sub>ODC</sub>	–0.5	1.0	2.5	V	Die		
Output Amplifier Bandwidth	f <sub>-3dB</sub>	–	250	–	MHz	Die		6
Output Amplifier Impedance	R <sub>OUT</sub>	–	140	–	Ω	Die	TBD	
Output Amplifier Sensitivity (Normal output)	ΔV/ΔN	–	44	–	μV/e <sup>-</sup>	Design		
Output Amplifier Sensitivity (Floating Gate Amplifier)	ΔV/ΔN (FG)	–	6.2	–	μV/e <sup>-</sup>	Design		
Quantum Efficiency (Peak)	QE <sub>MAX</sub>				%	Design		
Monochrome		–	50%	–				
Red		–	33%	–				
Green		–	41%	–				
Blue		–	43%	–				
Power					W	Design		
4-Output Mode (20MHz)		–	0.8	–				
4-Output Mode (40MHz)		–	0.7	–				
2-Output Mode (20MHz)		–	0.5	–				
2-Output Mode (40MHz)		–	0.5	–				
1-Output Mode (20MHz)		–	0.4	–				
1-Output Mode (40MHz)		–	0.4	–				

1. Per color
2. Value is over the range of 10% to 90% of photodiode saturation.
3. The operating value of the substrate reference voltage, V<sub>AB</sub>, can be read from pin 60.
4. At 40 MHz.
5. Uses 20LOG (P<sub>Ne</sub> / n<sub>e-T</sub>).
6. Calculated from f<sub>-3dB</sub> = 1 / 2π · R<sub>OUT</sub> · C<sub>LOAD</sub> where C<sub>LOAD</sub> = 5 pF.

TYPICAL PERFORMANCE CURVES

Quantum Efficiency

Monochrome with Microlens

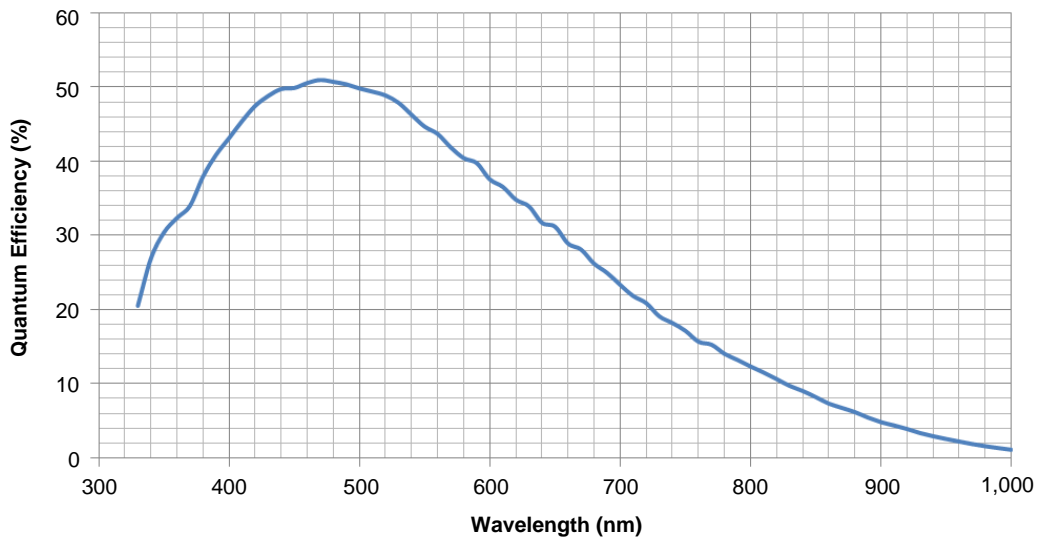


Figure 5. Monochrome QE with Microlens

Color (Bayer RGB) with Microlens

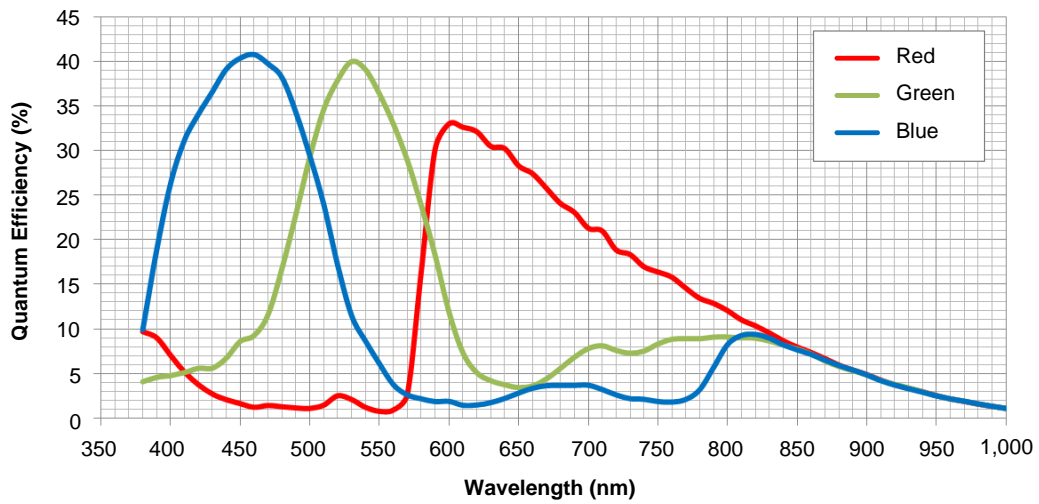
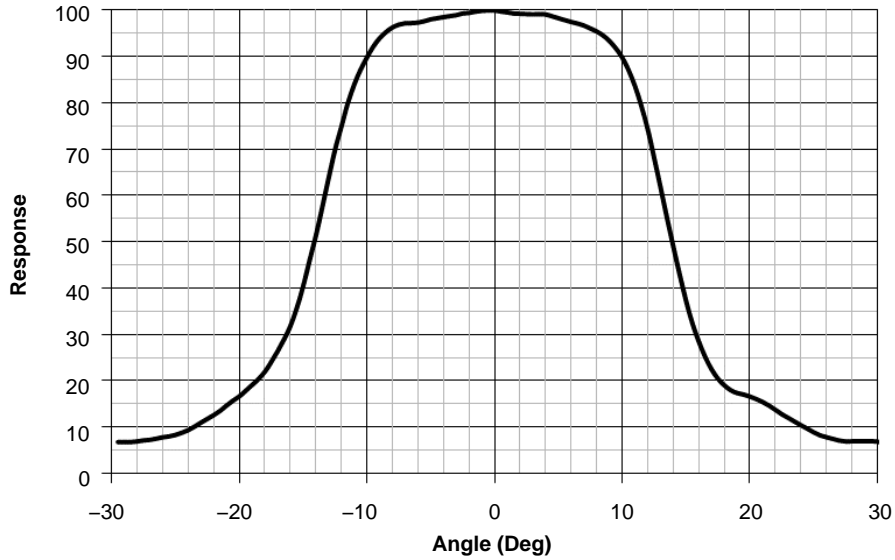


Figure 6. Color (Bayer RGB) QE with Microlens

**Angular Response**

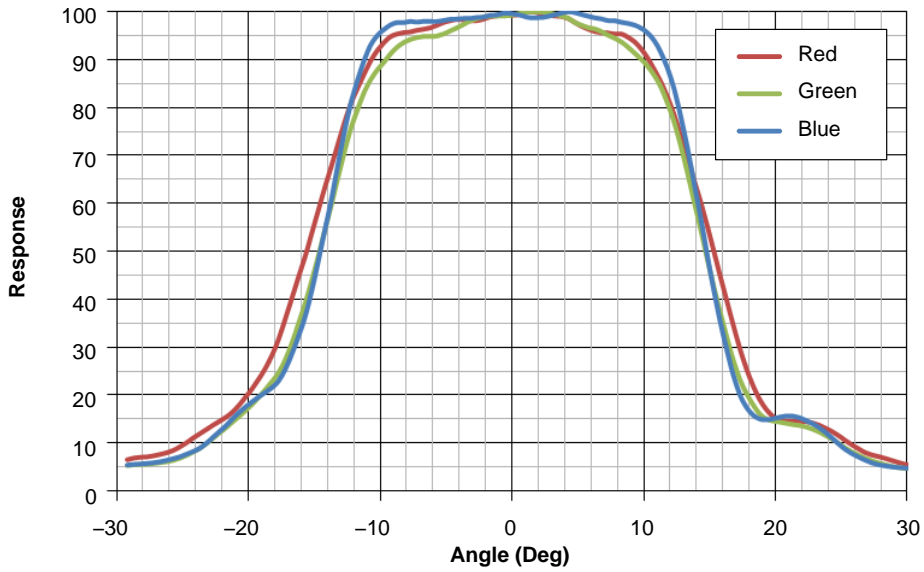
The incident light angle is varied in a plane parallel to the HCCD.

*Monochrome with Microlens*



**Figure 7. Monochrome with Microlens Angle Response**

*Color (Bayer RGB) with Microlens*



**Figure 8. Color with Microlens Angle Response**

Frame Rates

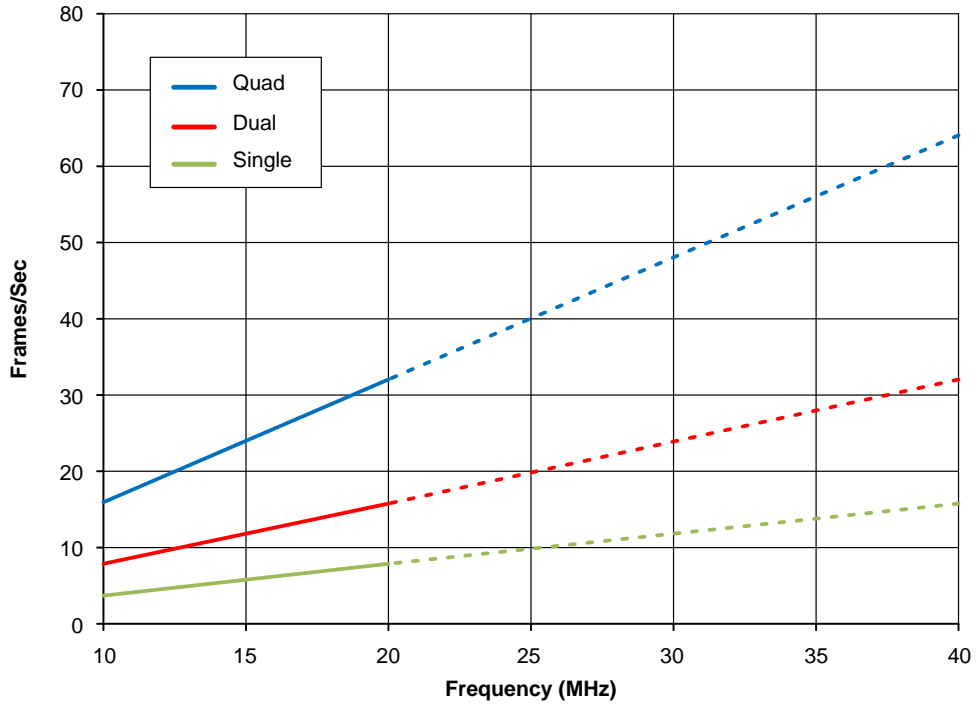


Figure 9. Frame Rates vs. Frequency

## DEFECT DEFINITIONS

Table 7. DEFECT DEFINITIONS

Description	Threshold/Definition	Maximum Number Allowed	Notes
Major Dark Field Defective Bright Pixel	$\geq 10$ mV	20	1, 2
Major Bright Field Defective Dark Pixel	$\geq 12\%$	20	
Minor Dark Field Defective Bright Pixel	$\geq 5$ mV	200	
Cluster Defect	A Group of 2 to 10 Contiguous Major Defective Pixels	8	3
Column Defect	A Group of More than 10 Contiguous Major Dark Defective Pixels along a Single Column or 10 Contiguous Bright Defective Pixels along a Single Column	0	3, 4

1. The thresholds are defined for an operating temperature of 0°C, quad output mode, and a readout rate of 20 MHz. For operation at 22°C, thresholds of 260 mV for major bright pixels and 35 mV for minor bright pixels would give approximately the same numbers of defects.
2. For the color device, a bright field defective pixel deviates by 12% with respect to pixels of the same color.
3. Column and cluster defects are separated by no less than 2 good pixels in any direction (excluding single pixel defects).
4. Low exposure dark column defects are not counted at temperatures above 0°C.

## OPERATION

**Table 8. ABSOLUTE MAXIMUM RATINGS**

(Absolute maximum rating is defined as a level or condition that should not be exceeded at any time per the description. If the level or the condition is exceeded, the device will be degraded and may be damaged. Operation at these values will reduce MTTF.)

Description	Symbol	Minimum	Maximum	Units	Notes
Operating Temperature	T <sub>OP</sub>	-70	40	°C	1
Humidity	RH	5	90	%	2
Output Bias Current	I <sub>OUT</sub>	-	5	mA	3
Off-Chip Load	CL	-	10	pF	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- Noise performance will degrade at higher temperatures.
- T = 25°C. Excessive humidity will degrade MTTF.
- Total for all outputs. Maximum current is -15 mA for each output. Avoid shorting output pins to ground or any low impedance source during operation. Amplifier bandwidth increases at higher current and lower load capacitance at the expense of reduced gain (sensitivity).

**Table 9. ABSOLUTE MAXIMUM VOLTAGE RATINGS BETWEEN PINS AND GROUND**

Description	Minimum	Maximum	Units	Notes
VDD23ab, VDD23cd	-0.4	17.5	V	1
VOUT2, VOUT3	-0.4	15	V	
VDD1, VOUT1	-0.4	7.0	V	
V1B, V1T	ESD - 0.4	ESD + 22.0	V	
V2B, V2T, V3B, V3T, V4B, V4T	ESD - 0.4	ESD + 14.0	V	
H1S, H1B, H2S, H2B, H1BEM, H2BEM, H2SL, H2X, H2SW2, H2SW3, RG1, RG2, RG3	-0.4	10	V	1
H1SEM, H2SEM	-0.4	20	V	
ESD	-9.0	0.0	V	
SUB	6.5	40	V	2, 3

- "α" denotes a, b, c or d.
- Refer to Application Note *Using Interline CCD Image Sensors in High Intensity Visible Lighting Conditions*.
- The measured value for V<sub>SUBREF</sub> is a diode drop higher than the recommended minimum V<sub>SUB</sub> bias.

**Power-Up and Power-Down Sequence**

SUB and ESD power up first, then power up all other biases in any order. No pin may have a voltage less than ESD at any time. All HCCD pins must be greater than or equal to GND at all times. The SUB<sub>REF</sub> pin will not become valid

until VDD23ab has been powered, therefore the SUB voltage cannot be directly derived from the SUB<sub>REF</sub> pin. The SUB pin should be at least 4 V before powering up VDD23ab or VDD23cd.

**Table 10. DC BIAS OPERATING CONDITIONS**

Description	Pins	Symbol	Minimum	Nominal	Maximum	Units	Maximum DC Current	Notes
Output Amplifier Return	VSS1	V <sub>SS1</sub>	-8.3	-8.0	-7.7	V	4 mA	
Output Amplifier Supply	VDD1	V <sub>DD1</sub>	4.5	5.0	6.0	V	15 mA	
Output Amplifier Supply	VDD23	V <sub>DD23</sub>	+14.7	+15.0	+15.3	V	37.0 mA	1
Ground	GND	GND	0.0	0.0	0.0	V	17.0 mA	
Substrate	SUB	V <sub>SUB</sub>	6.5	V <sub>SUBREF</sub> - 0.5	V <sub>SUBREF</sub> + 28	V	Up to 1 mA (Determined by Photocurrent)	2
ESD Protection Disable	ESD	ESD	-8.3	-8.0	-7.7	V	0.25 mA	
Output Bias Current	VOUT	I <sub>OUT</sub>	2.0	2.5	5.0	mA		

- VDD bias pins for all four quadrants must be maintained at 15 V during operation.
- For each image sensor the voltage output on the V<sub>SUBREF</sub> pin is programmed to be one diode drop, 0.5 V, above the nominal SUB voltage. The voltage output on V<sub>SUBREF</sub> is unique to each image sensor and may vary from 6.5 to 10.0 V. The output impedance of V<sub>SUBREF</sub> is approximately 100 k. The applied V<sub>SUB</sub> should be one diode drop lower than the V<sub>SUBREF</sub> value measured on the device, when V<sub>DD23</sub> is at the specified voltage.

AC Operating Conditions

Table 11. CLOCK LEVELS

Pin	Function	HCCD and RG					
		Low Level			Amplitude		
		Low	Nominal	High	Low	Nominal	High
H2B(a,b,c,d)	Reversible HCCD Barrier 2	-0.2	0.0	0.2	3.1	3.3	3.6
H1B(a,b,c,d)	Reversible HCCD Barrier 1	-0.2	0.0	0.2	3.1	3.3	3.6
H2S(a,b,c,d)	Reversible HCCD Storage 2	-0.2	0.0	0.2	3.1	3.3	3.6
H2B(a,b,c,d)	Reversible HCCD Storage 1	-0.2	0.0	0.2	3.1	3.3	3.6
H2SW(2,3)(a,b,c,d)	HCCD Switch 2 and 3	-0.2	0.0	0.2	3.1	3.3	3.6
H2L(a,b,c,d)	HCCD Last Gate	-0.2	0.0	0.2	3.1	3.3	3.6
H2X(a,b,c,d)	Floating Gate Exit	-0.2	0.0	0.2	6.0	6.4	6.8
RG1(a,b,c,d)	Floating Gate Reset	Cap			3.1	3.3	3.6
RG(2,3)(a,b,c,d)	Floating Diffusion Reset	Cap			3.1	3.3	3.6
H1BEM(a,b,c,d)	Multiplier Barrier 1	-0.2	0.0	0.2	4.6	5.0	5.4
H2BEM(a,b,c,d)	Multiplier Barrier 2	-0.2	0.0	0.2	4.6	5.0	5.4
H1SEM(a,b,c,d)	Multiplier Storage 1	-0.3	0.0	0.3	7.0	-	18.0
H2SEM(a,b,c,d)	Multiplier Storage 2	-0.3	0.0	0.3	7.0	-	18.0

1. HCCD Operating Voltages. There can be no overshoot on any horizontal clock below -0.4 V: the specified absolute minimum. The H1SEM and H2SEM clock amplitudes need to be software programmable to adjust the charge multiplier gain.
2. Reset Clock Operation: The RG1, RG2, and RG3 signals must be capacitive coupled into the image sensor with a 0.01 μF to 0.1 μF capacitor. The reset clock overshoot can be no greater than 0.3 V, as shown in Figure 10, below:

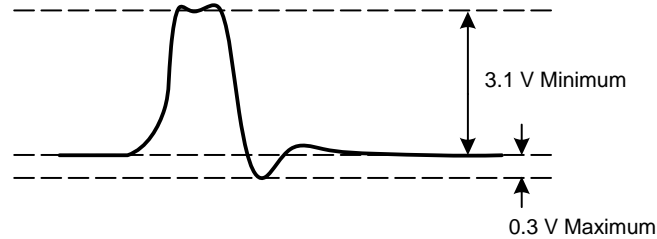


Figure 10. RG Clock Overshoot

Clock Capacitances

Pin	Capacitance (pF)
H1Sa	76
H1Sb	76
H1Sc	76
H1Sd	76
H2Sa	76
H2Sb	76
H2Sc	76
H2Sd	76

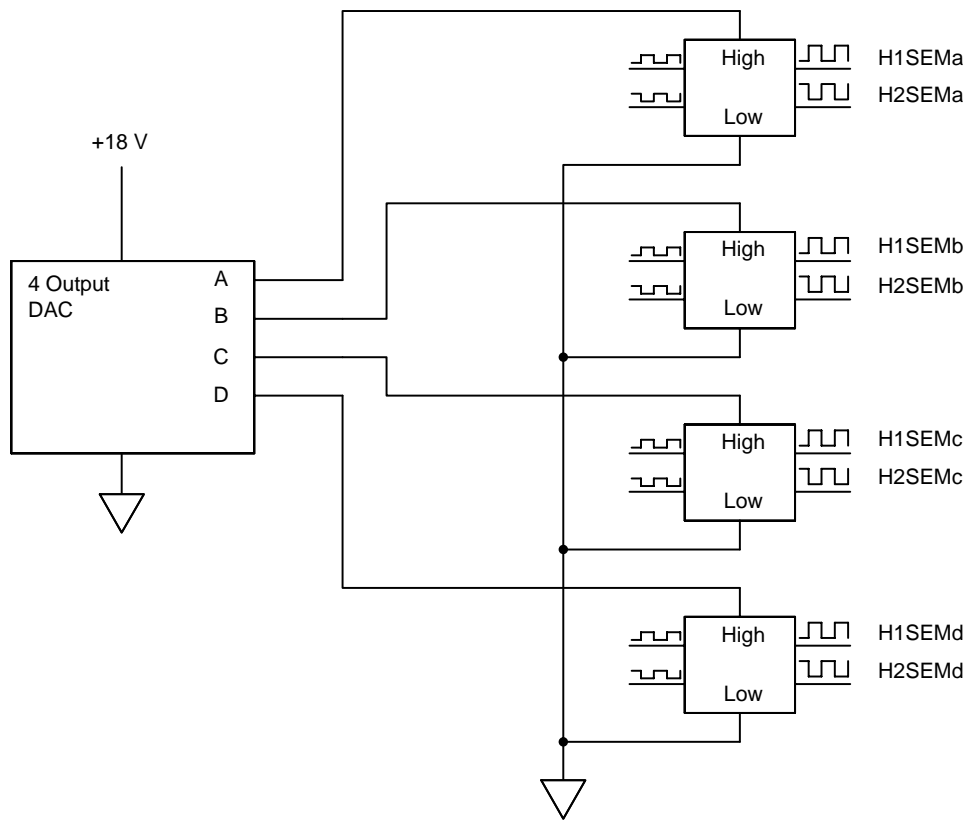
Pin	Capacitance (pF)
H1Ba	39
H1Bb	39
H1Bc	39
H1Bd	39
H2Ba	39
H2Bb	39
H2Bc	39
H2Bd	39

Pin	Capacitance (pF)
H1BEMa	56
H1BEMb	56
H1BEMc	56
H1BEMd	56
H2BEMa	56
H2BEMb	56
H2BEMc	56
H2BEMd	56

Pin	Capacitance (pF)
H1SEMa	66
H1SEMb	66
H1SEMc	66
H1SEMd	66
H2SEMa	66
H2SEMb	66
H2SEMc	66
H2SEMd	66

NOTE: The capacitances of all other HCCD pins is 15 pF or less.

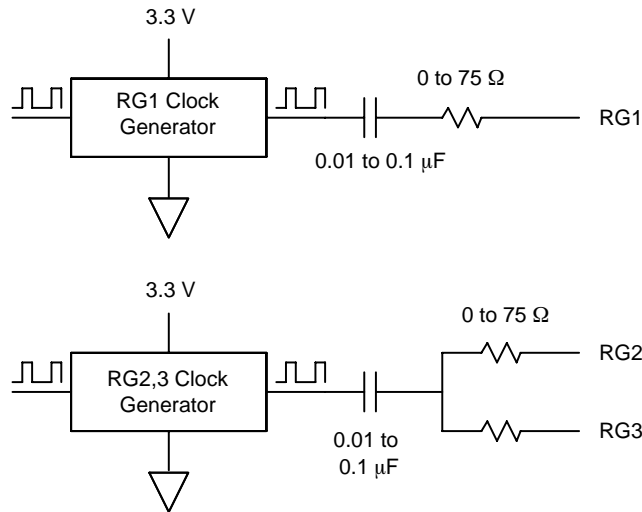




**Figure 11. EMCCD Clock Adjustable Levels**

For the EMCCD clocks, each quadrant must have independently adjustable high levels. All quadrants have a common low level of GND. The high level adjustments

must be software controlled to balance the gain of the four outputs.



**Figure 12. Reset Clock Drivers**

The reset clock drivers must be coupled by capacitors to the image sensor. The capacitors can be anywhere in the range 0.01 to 0.1  $\mu\text{F}$ . The damping resistor values would

vary between 0 and 75  $\Omega$  depending on the layout of the circuit board.

**Table 12. VCCD**

Pin	Function	Low	Nominal	High
V(1,2,3,4)(T,B)	Vertical CCD Clock, Low Level	-8.0	-8.0	-6
V(1,2,3,4)(T,B)	Vertical CCD Clock, Mid Level	-0.2	0	0.2
V(1)(T,B)	Vertical CCD Clock, High (3 <sup>rd</sup> ) Level	8.5	9.0	12.5

1. The Vertical CCD operating voltages. The VCCD low level will be -8.0 V for operating temperatures of 0°C and above. Below 0°C the VCCD low level should be increased for optimum noise performance.

**Table 13. BIAS VOLTAGES**

Pin	Function	Low	Nominal	High
ESD	ESD	-8.3	-8.0	-7.7
SUB (Notes 1, 2)	Electronic Shutter	$V_{SUB\_REF} + 22$	-	$V_{SUB\_REF} + 28$
VDD1(a,b,c,d)	Floating Gate Power	4.5	5.0	6.0
VSS1(a,b,c,d)	Floating Gate Return	-8.3	-8.0	-7.7
VDD(2,3)(a,b,c,d)	Floating Diffusion Power	14.7	15.0	15.3
VOU1(a,b,c,d)	Floating Gate Output Range	-0.5	1.0	2.5
VOU(2,3)(a,b,c,d)	Floating Diffusion Output Range	8.0	10.0	12.0

1. Caution: Do not clock the EMCCD register while the electronic shutter pulse is high.  
 2. The substrate bias (SUB) should normally be kept at  $V_{AB}$ , which can be read from Pin 60. However, this value was determined from operation at 0°C, and has an approximate temperature dependence of 0.01 V/degree.

**Device Identification**

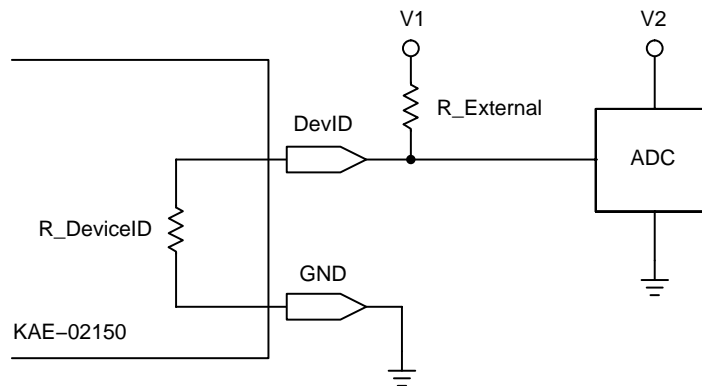
The device identification pin (DevID) may be used to determine which ON Semiconductor 5.5 micron pixel interline CCD sensor is being used.

**Table 14. DEVICE IDENTIFICATION**

Description	Pins	Symbol	Minimum	Nominal	Maximum	Units	Maximum DC Current	Notes
Device Identification	DevID	DevID	44,000	50,000	56,000	$\Omega$	0.3 mA	1, 2, 3

1. Nominal value subject to verification and/or change during release of preliminary specifications.  
 2. If the Device Identification is not used, it may be left disconnected.  
 3. After Device Identification resistance has been read during camera initialization, it is recommended that the circuit be disabled to prevent localized heating of the sensor due to current flow through the R\_DeviceID resistor.

*Recommended Circuit*



**Figure 13. Device Identification Recommended Circuit**

## THEORY OF OPERATION

### Image Acquisition

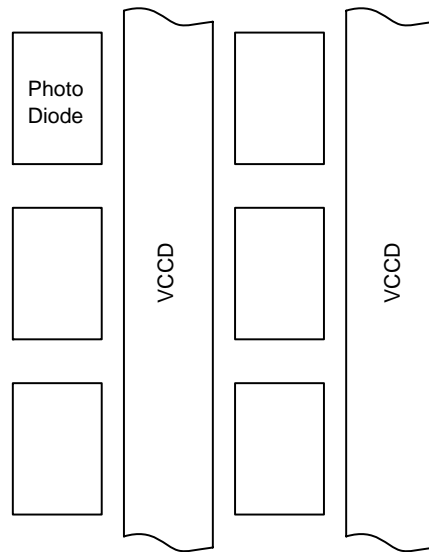


Figure 14. Illustration of 2 Columns and 3 Rows of Pixels

This image sensor is capable of detecting up to 20,000 electrons with a small signal noise floor of 1 electron all within one image. Each  $5.5\ \mu\text{m}$  square pixel, as shown in Figure 14 above, consists of a light sensitive photodiode and a portion of the vertical CCD (VCCD). Not shown is a microlens positioned above each photodiode to focus light away from the VCCD and into the photodiode. Each photon incident upon a pixel will generate an electron in the photodiode with a probability equal to the quantum efficiency.

The photodiode may be cleared of electrons (electronic shutter) by pulsing the SUB pin of the image sensor up to a voltage of 30 V to 40 V ( $V_{\text{SUB\_REF}} + 22\ \text{V}$  to  $V_{\text{SUB\_REF}} + 28\ \text{V}$ ) for a time of at least  $1\ \mu\text{s}$ . When the SUB pin is above 30 V, the photodiode can hold no electrons, and the electrons flow downward into the substrate. When the voltage on SUB drops below 30 V, the integration of electrons in the photodiode begins. The HCCD clocks should be stopped when the electronic shutter is pulsed, to avoid having the large voltage pulse on SUB coupling into the video outputs and altering the EMCCD gain.

It should be noted that there are certain conditions under which the device will have no anti-blooming protection: when the V1T and V1B pins are high, very intense illumination generating electrons in the photodiode will flood directly into the VCCD. When the electronic shutter pulse overlaps the V1T and V1B high-level pulse that transfers electrons from the photodiode to the VCCD, then photo-electrons will flow to the substrate and not the VCCD. This condition may be desirable as a means to obtain very short integration times.

The VCCD is shielded from light by metal to prevent detection of more photons. For very bright spots of light, some photons may leak through or around the metal light shield and result in electrons being transferred into the VCCD. This is called image smear.

### Image Readout

At the start of image readout, the voltage on the V1T and V1B pins is pulsed from 0 V up to the high level for at least  $1\ \mu\text{s}$  and back to 0 V, which transfers the electrons from the photodiodes into the VCCD. If the VCCD is not empty, then the electrons will be added to what is already in the VCCD. The VCCD is read out one row at a time. During a VCCD row transfer, the HCCD clocks are stopped. All gates of type H1 stop at the high level and all gates of type H2 stop at the low level. After a VCCD row transfer, charge packets of electrons are advanced one pixel at a time towards the output amplifiers by each complimentary clock cycle of the H1 and H2 gates.

The charge multiplier has a maximum charge handling capacity (after gain) of 20,000 electrons. This is not the average signal level. It is the maximum signal level. Therefore, it is advisable to keep the average signal level at 15,000 electrons or less to accommodate a normal distribution of signal levels. For a charge multiplier gain of 20x, no more than  $15,000/20 = 750$  electrons should be allowed to enter the charge multiplier. Overfilling the charge multiplier beyond 20,000 electrons will shorten its useful operating lifetime. In addition, sending signals larger than 180–200 electrons into the EMCCD will produce images with lower signal-to-noise ratio than if they were read out of the normal floating diffusion output. See Application Note AND9244.

To prevent overfilling the charge multiplier, a non-destructive floating gate output amplifier (VOUT1) is

provided on each quadrant of the image sensor as shown in Figure 15.

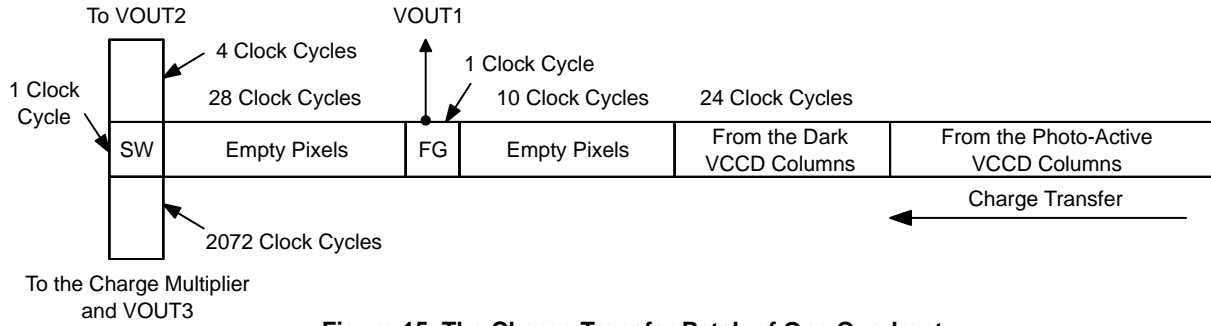
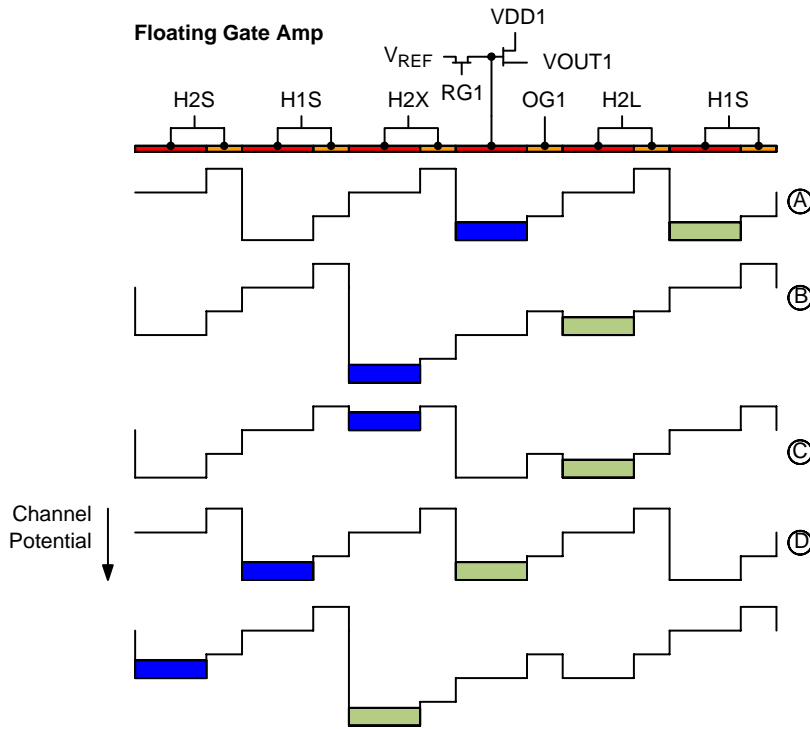


Figure 15. The Charge Transfer Patch of One Quadrant

The non-destructive floating gate output amplifier is able to sense how much charge is present in a charge packet without altering the number of electrons in that charge packet. This type of amplifier has a low charge-to-voltage conversion gain (about  $6.2 \mu\text{V}/e^-$ ) and high noise (about 60 electrons), but it is being used only as a threshold detector, and not an imaging detector. Even with 60 electrons of noise, it is adequate to determine whether a charge packet is greater than or less than the recommended threshold of 180 electrons.

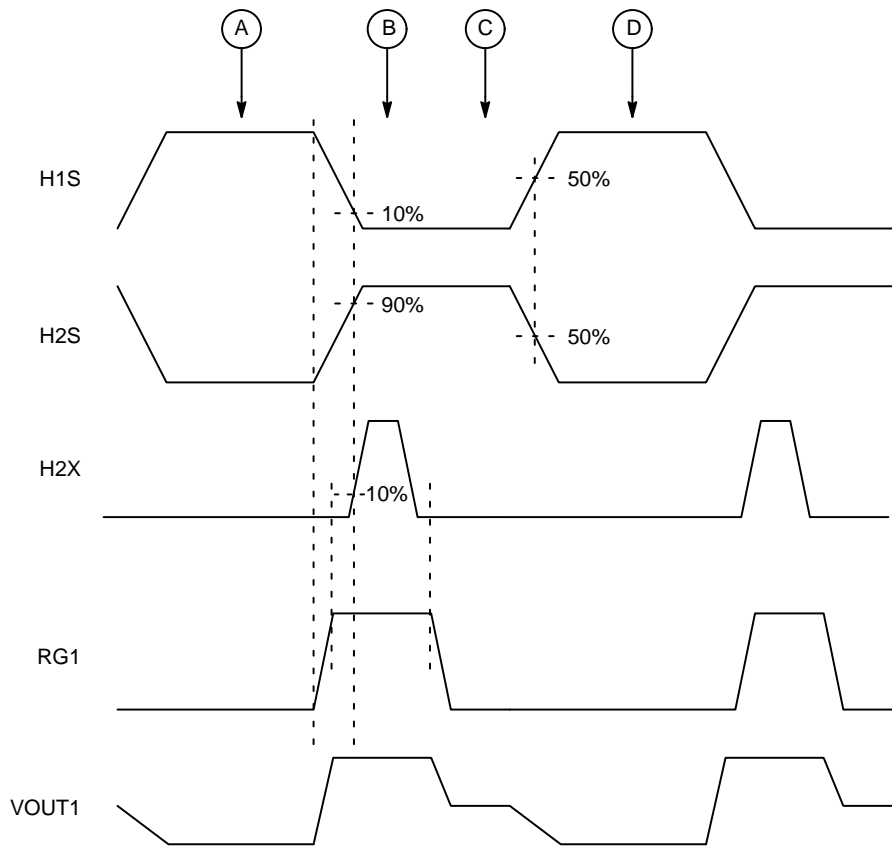
After one row has been transferred from the VCCD into the HCCD, the HCCD clock cycles should begin. After 10 clock cycles, the first dark VCCD column pixel will arrive at VOUT1. After another 24 (34 total) clock cycles, the first photo-active charge packet will arrive at VOUT1.

The transfer sequence of a charge packet through the floating gate amplifier is shown in Figure 16 below. The time steps of this sequence are labeled A through D, and are indicated in the timing diagram shown as Figure 17. The RG1 gate is pulse high during the time that the H2X gate is pulsed high. This holds the floating gate at a constant voltage so the H2X gate can pull the charge packet out of the floating gate. The RG1 pulse should be at least as wide as the H2X pulse. The H2X pulse width should be at least 12 ns. The rising edge of H2X relative to the falling edge of H1S is critical. The H2X pulse cannot begin its rising edge transition until the H1S edge is less than 0.4 V. If the H2X rising edge comes too soon then there may be some backwards flow of charge for signals above 10,000 electrons.



NOTE: The blue and green rectangles represent two separate charge packets. The direction of charge transfer is from right to left.

Figure 16. Charge Packet Transfer Sequence through the Floating Gate Amplifier

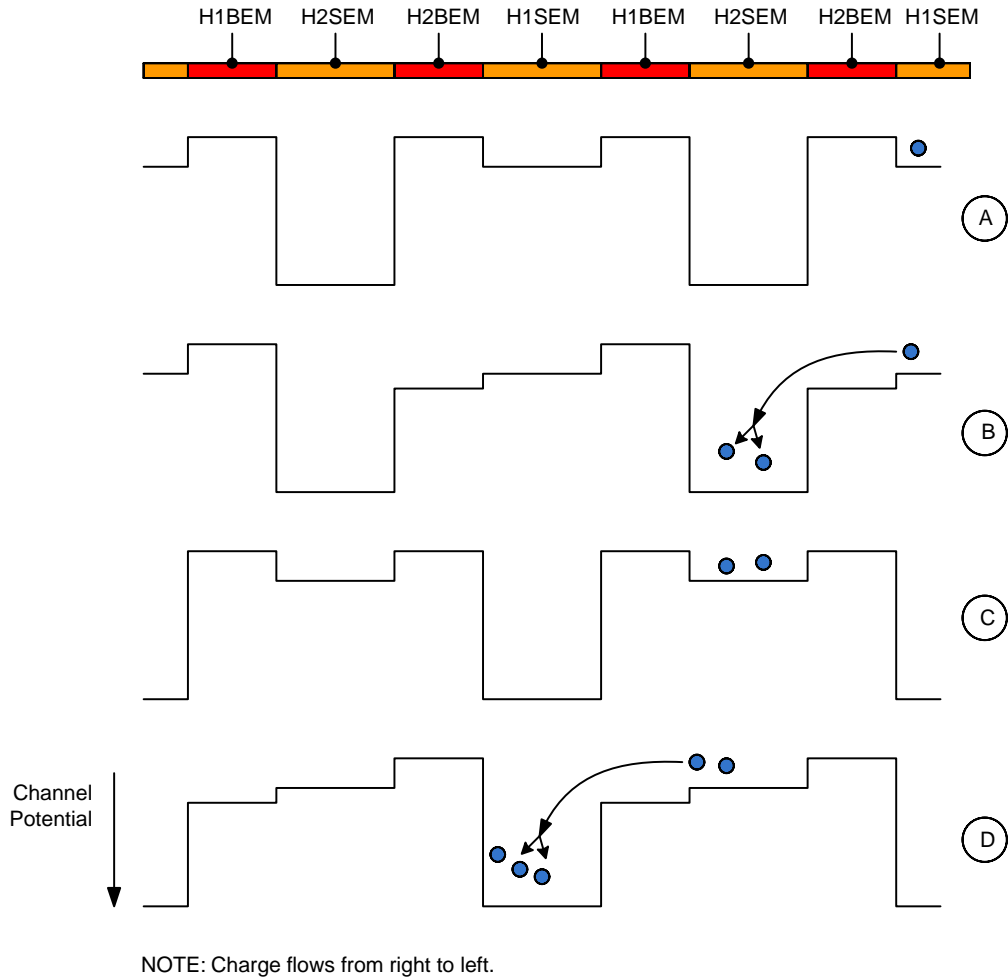


**Figure 17. Timing Signals that Control the Transfer of Charge through the Floating Gate Amplifier**

The charge packet is transferred under the floating gate on the falling edge of H2L. When this transfer takes place the floating gate is not connected to any voltage source. The presence of charge under the gate causes a change in voltage on the floating gate according to  $V = Q / C$ , where  $Q$  is the size of the charge packet and  $C$  is the capacitance of the floating gate. With an output sensitivity of  $6.2 \mu\text{V}/e^-$ , each electron on the floating gate would give a  $6.2 \mu\text{V}$  change in VOUT1 voltage. Therefore if the decision threshold is to only allow charge packets of 180 electrons or less into the charge multiplier, this would correspond to  $180 \times 6.2 = 1.1 \text{ mV}$ . If the video output is less than 1.1 mV, then the camera must set the timing of the H2SW2 and

H2SW3 pins to route the charge packet to the charge multiplier. This action must take place 28 clock cycles after the charge packet was under the floating gate amplifier. The 28 clock cycle delay is to allow for pipeline delays of the A/D converter inside the analog front end. The timing generator must examine the output of the analog front end and dynamically alter the timing on H2SW2 and H2SW3. To route a charge packet to the charge multiplier (VOUT3), H2SW2 is held at GND and H2SW3 is clocked with the same timing as H2S for that one clock cycle. To route a charge packet to the low gain output amplifier (VOUT2), H2SW3 is held at GND and H2SW2 is clocked with the same timing as H2S for that one clock cycle.

EMCCD OPERATION



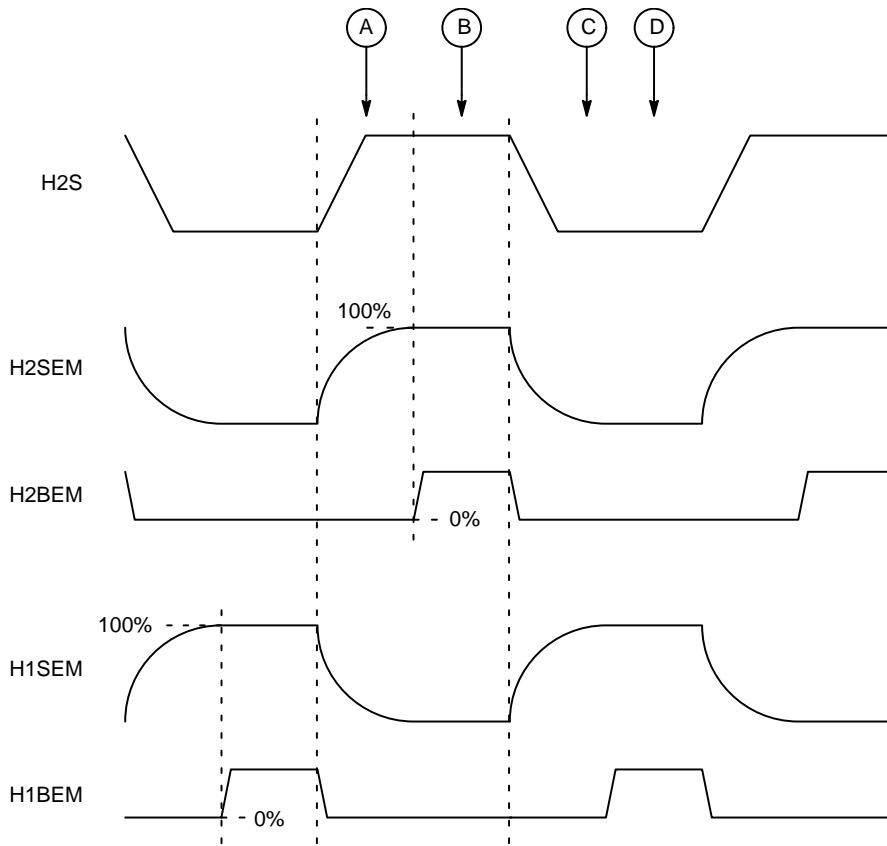
**Figure 18. The Charge Multiplication Process**

The charge multiplication process, shown in Figure 18 above, begins at time step A, when an electron is held under the H1SEM gate. The H2BEM and H1BEM gates block the electron from transferring to the next phase until the H2SEM has reached its maximum voltage. When the H2BEM is clocked from 0 to 5 V, the channel potential under H2BEM increases until the electron can transfer from H1SEM to H2SEM. When the H2SEM gate is above 10 V, the electric field between the H2BEM and H2SEM gates gives the electron enough energy to free a second electron which is collected under H2SEM. Then the voltages on H2BEM and

H2SEM are both returned to 0 V at the same time that H1SEM is ramped up to its maximum voltage. Now the process can repeat again with charge transferring into the H1SEM gate.

The alignment of clock edges is shown in Figure 19. The rising edge of the H1BEM and H2BEM gates must be delayed until the H1SEM or H2SEM gates have reached their maximum voltage. The falling edge of H1BEM and H2BEM must reach 0 V before the H1SEM or H2SEM reach 0 V. There are a total of 1,800 charge multiplying transfers through the EMCCD on each quadrant.

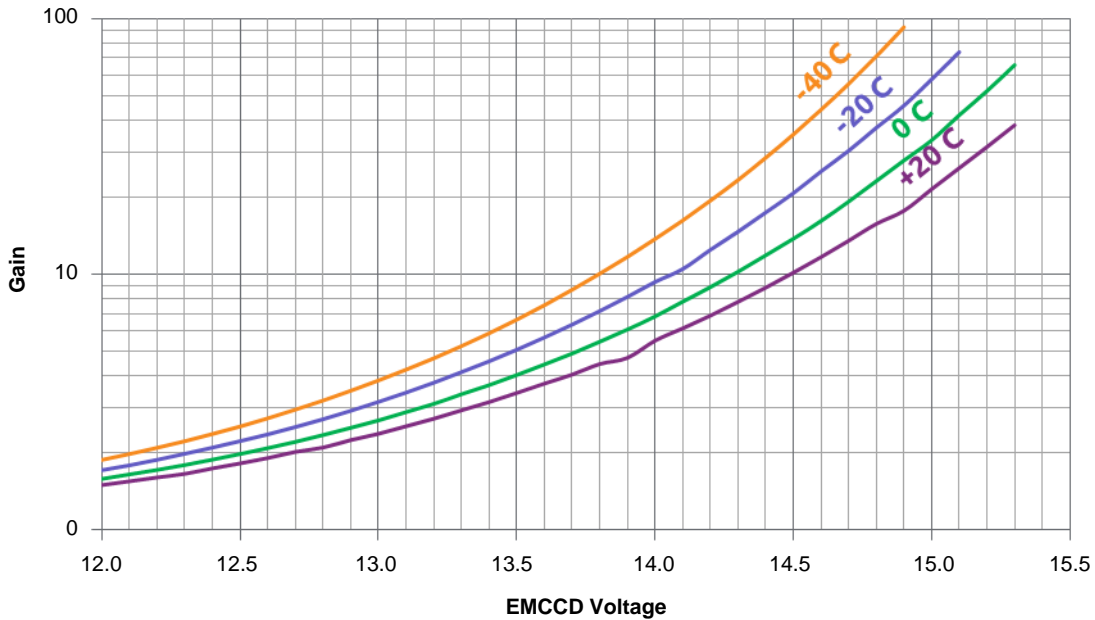
# KAE-02150



**Figure 19. The Timing Diagram for Charge Multiplication**

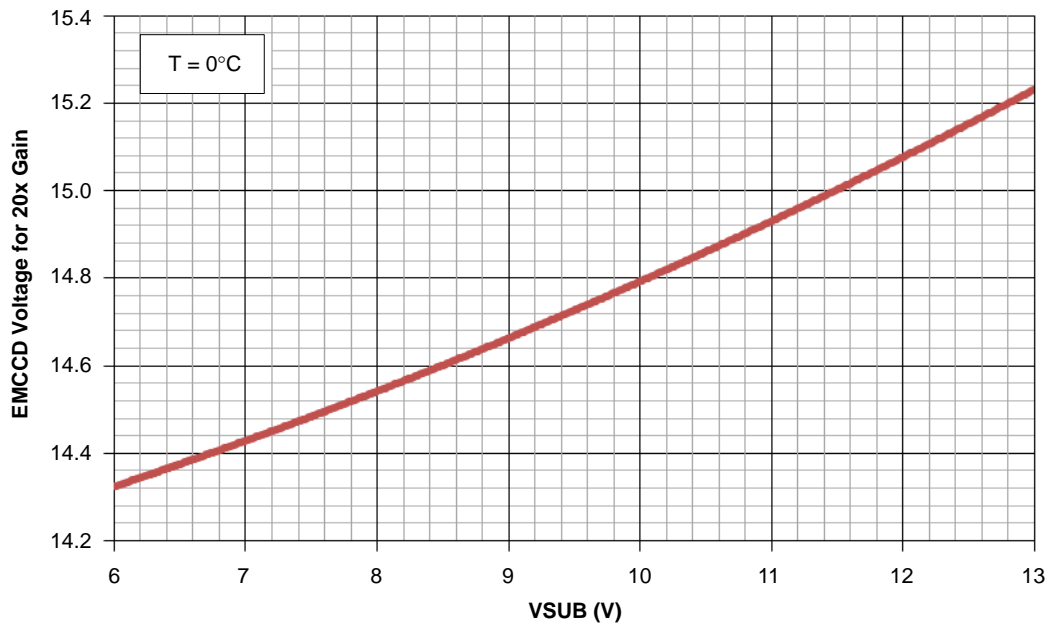
The amount of gain through the EMCCD will depend on temperature and H1SEM and H2SEM voltage as shown in

Figure 20. Gain also depends on substrate voltage, as shown in Figure 21, and on the input signal, as shown in Figure 22.



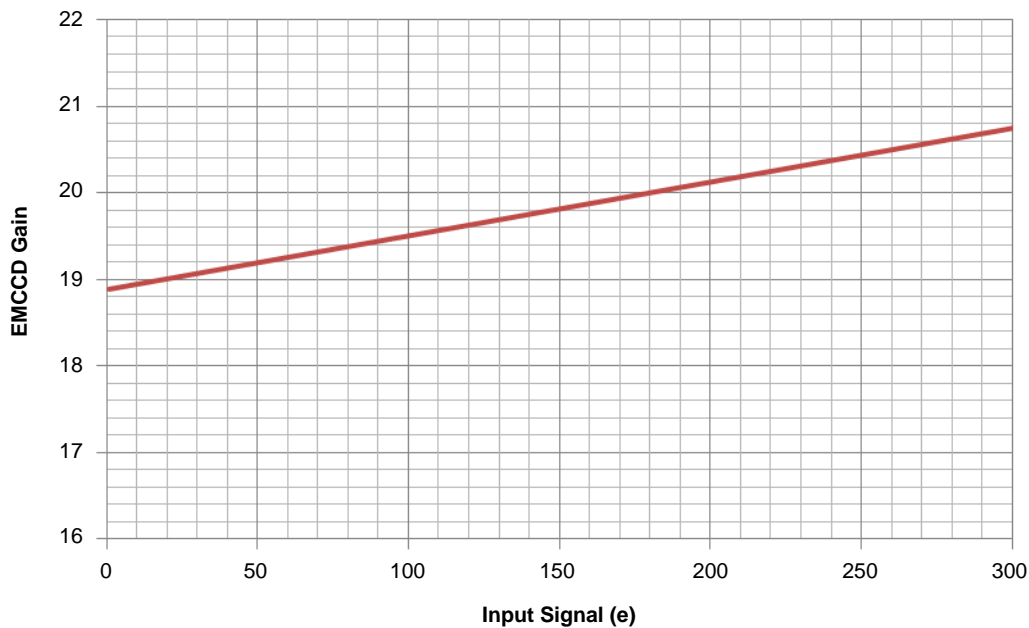
NOTE: This figure represents data from only one example image sensor, other image sensors will vary.

**Figure 20. The Variation of Gain vs. EMCCD High Voltage and Temperature**



NOTE: This figure represents data from only one example image sensor, other image sensors will vary.

**Figure 21. The Change in the Required EMCCD Voltage for a Gain of 20x vs. the Substrate Voltage**



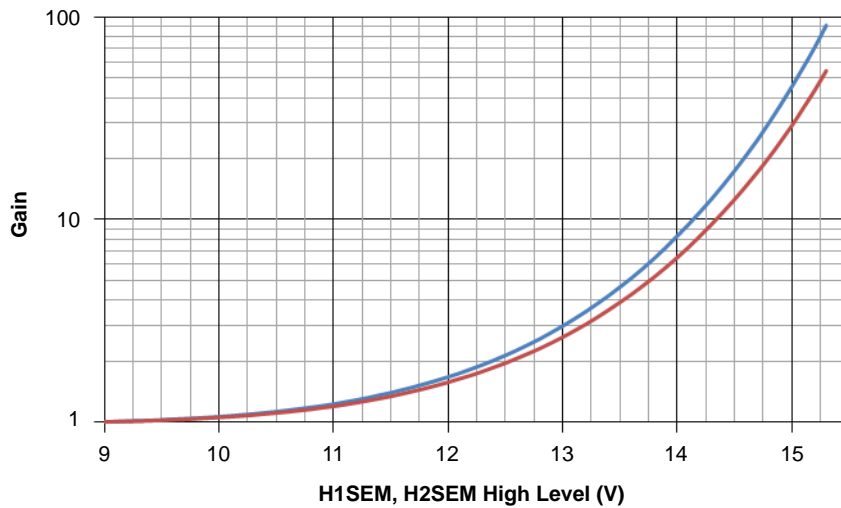
NOTE: The EMCCD voltage was set to provide 20x gain with an input of 180 electrons.

**Figure 22. EMCCD Gain vs. Input Signal**

If more than one output is used, then the EMCCD high level voltage must be independently adjusted for each quadrant. This is because each quadrant will require a slightly different voltage to obtain the same gain. In addition, the voltage required for a given gain differs

unpredictably from one image sensor to the next, as in Figure 23. Because of this, the gain vs. voltage relationship must be calibrated for each image sensor, although within each quadrant, the H1SEM and H2SEM high level voltage should be equal.

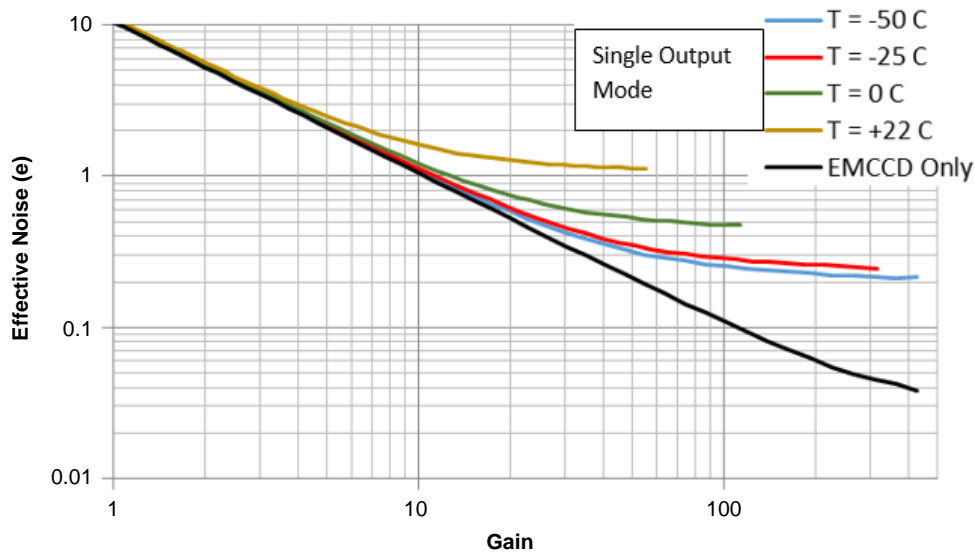




**Figure 23. An Example Showing How Two Image Sensors Can Have Different Gain vs. Voltage Curves**

The effective output noise of the image sensor is defined as the noise of the output signal divided by the gain. This is measured with zero input signal to the EMCCD. Figures 24 and 25 show the EMCCD by itself has a very low noise that goes as the noise at gain = 1 divided by the gain. The EMCCD has very little clock-induced charge and does not require elaborate sinusoidal waveform clock drivers. Simple square wave clock drivers with a resistor between the

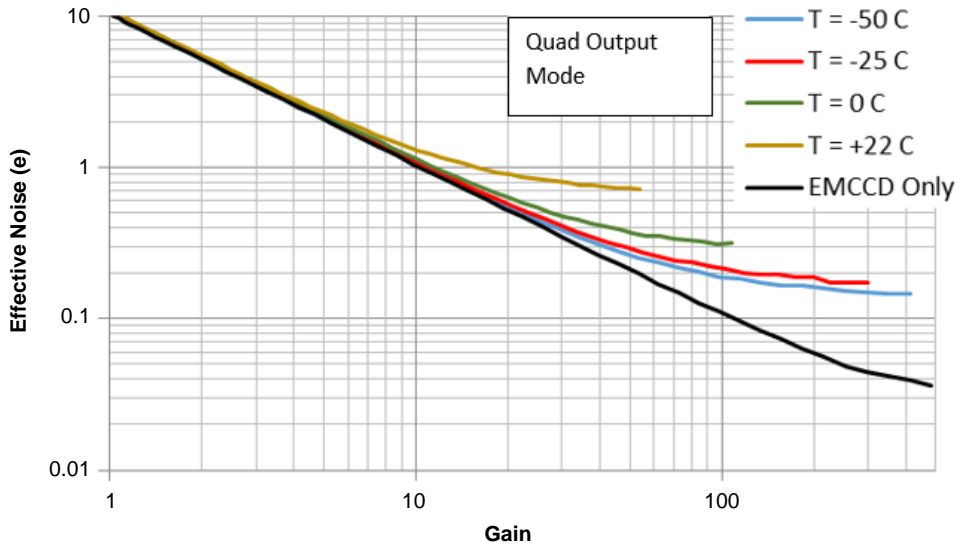
driver and sensor for a small RC time constant are all that is needed. However, the pixel array may acquire spurious charge as a function of VCCD clock driver characteristics. Also, the VCCD is sensitive to hot electron luminescence emitted from the output amplifiers during image readout. These two factors limit the noise floor of the total imaging array.



NOTE: This figure represents data from only one example image sensor, other image sensors will vary.

**Figure 24. EMCCD Output Noise vs. EMCCD Gain in Single Output Mode at -50 to 22°C**

# KAE-02150

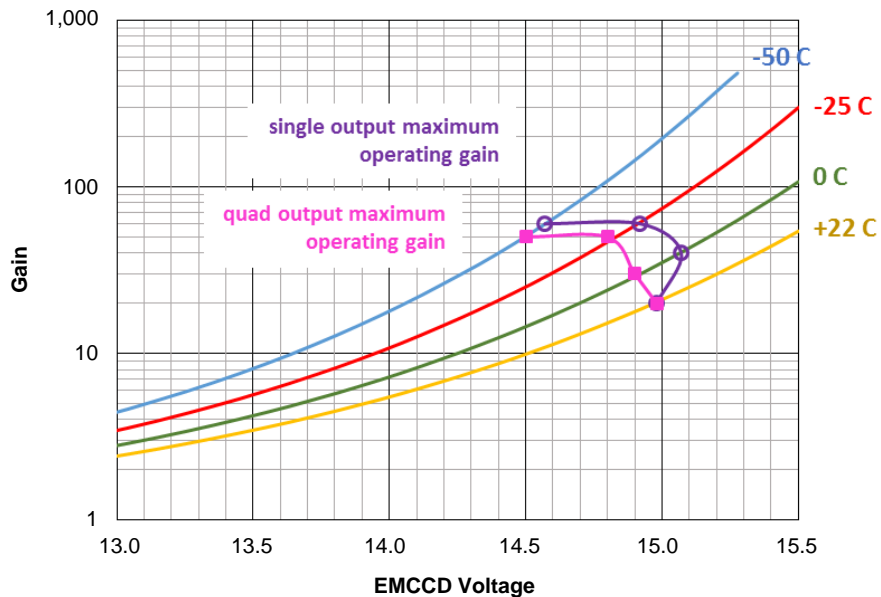


NOTE: This figure represents data from only one example image sensor, other image sensors will vary.

**Figure 25. EMCCD Output Noise vs. EMCCD Gain in Quad Output Mode at -50 to 22°C**

Because of these pixel array noise sources, it is recommended that the maximum gain used be 40x at 0°C, which typically gives a noise floor between 1e and 0.4e. Using higher gains will provide limited benefit and will degrade the signal to noise ratio due to the EMCCD excess noise factor. Furthermore, the image sensor is not limited by

dark current noise sources when the temperature is below 25°C. Therefore, cooling below 25°C will not provide a significant improvement to the noise floor. Lower temperatures will reduce the number of hot pixel defects observed only during image integration times longer than 1 s. Note the useful plot below:



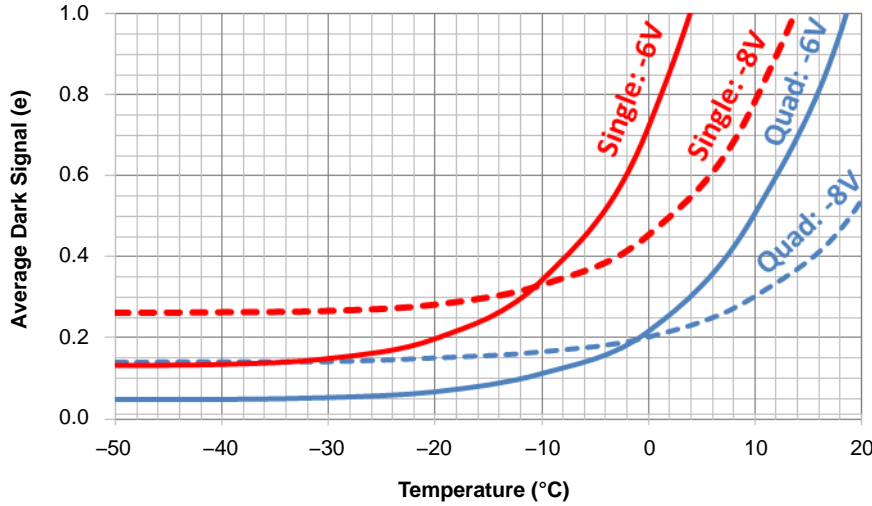
**CAUTION:** The EMCCD should not be operated near saturation for an extended period, as this may result in gain aging and permanently reduce the gain. It should be noted that device degradation associated with gain aging is not covered under the device warranty.

**Figure 26. Gain vs. Voltage with Maximum Recommended Operating Gains Marked**

**Choosing the Operating Temperature**

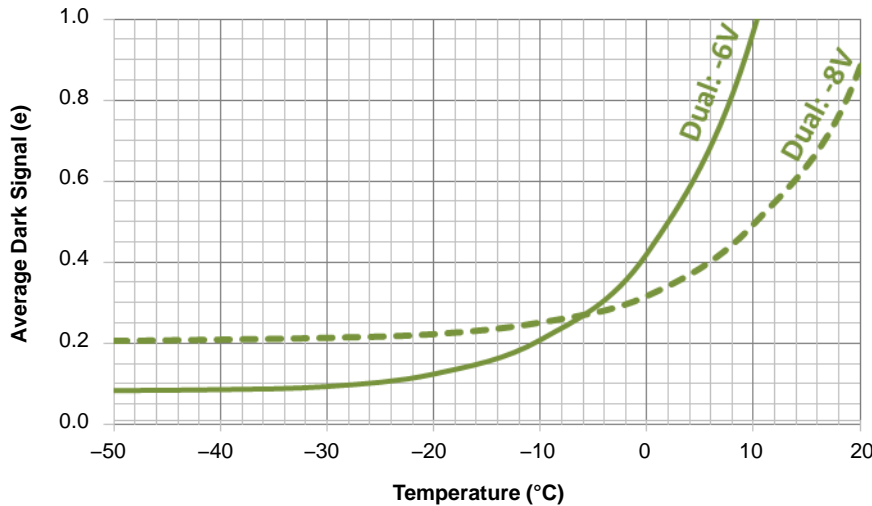
The reasons for lowering the operating temperature are to reduce dark current noise and to reduce image defects. The average dark signal from the VCCD and photodiodes must be less than 1e in order to have a total system noise less than 1e when using the EMCCD. Figures 27 and 28 illustrate how the amount of dark signal in the VCCD is dependent on both temperature and voltage, and may be used to choose the operating temperature and VCCD clock low level voltage.

When operating in quad output mode at 0°C either -6 V or -8 V may be used for the VCCD clock low level voltage because the dark signal will be equal. But if the operating temperature is -20°C then the VCCD clock low level voltage should be set to -6 V for the lowest VCCD dark signal. For single output mode, the VCCD clock low level voltage should be set to -6 V for temperatures of -10°C or lower and -8 V for temperatures of -10°C or higher.



NOTE: Both are for a HCCD frequency of 20 MHz. The VCCD low level voltage is shown for each curve.

**Figure 27. Dark Signal from VCCD in Quad and Single Output Modes**



**Figure 28. Dark Signal from VCCD in Dual Output Mode at HCCD Frequency 20 MHz**

The reason for the different temperature dependencies with the VCCD low level voltage at -6 V vs. -8 V is spurious charge generation (sometimes called clock-induced charge). When the VCCD low level is at -8 V, the VCCD is accumulated with holes, which reduces the rate of dark

current signal generation. However, the amount of clock induced charge is greater. At VCCD low level of -6 V, the VCCD is no longer accumulated with holes. So, clock-induced charge generation is less, but dark current is increased.

In quad output mode, the clock induced charge generated and the dark current signal are equal at T = 0°C. Below T = 0°C, the dark current signal is smaller than the clock induced charge, so -6 V is the best voltage. Above T = 0°C, the dark current signal dominates, and -8 V is the best voltage. The dark signal stops decreasing below T = -20°C because the VCCD is detecting hot electron luminescence from the output amplifiers during image readout.

In addition to dark noise, image defects also impact the optimum operating temperature. Although the average photodiode dark current is negligible at temperatures below 20°C, as shown by Figure 29, the number of photodiode hot-pixel defects is a function of temperature and will decrease with lower temperature.

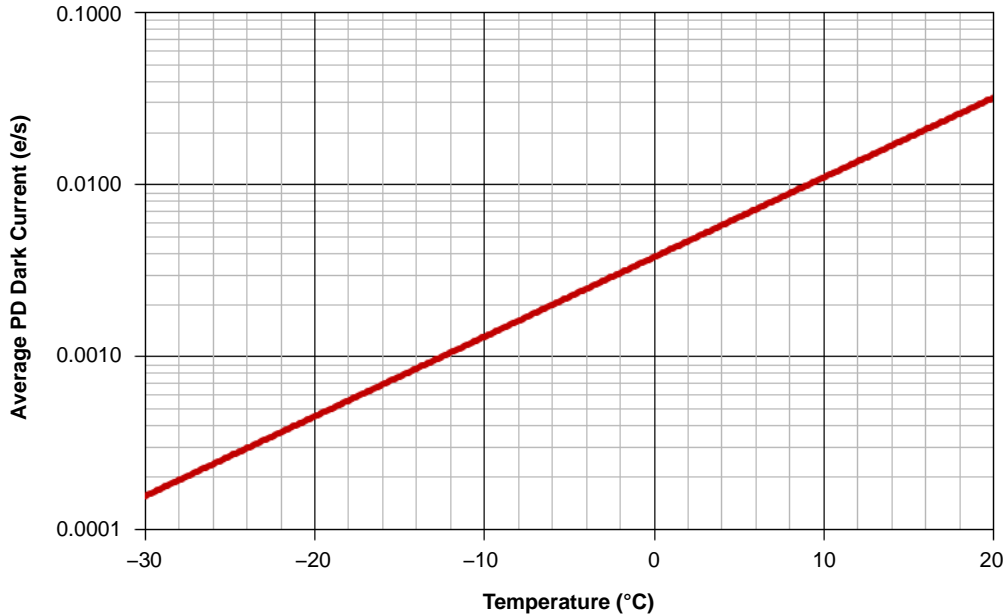


Figure 29. Photodiode Dark Current vs. Temperature

Note that the preceding figures are representative data only, and are not intended as a defect specification.

**Choosing the Charge Switch Threshold**

The floating gate output amplifier (VOUT1) is used to decide the routing of a pixel at the charge switch. Pixels with large signals should be routed to the normal floating diffusion amplifier at VOUT2. Pixels with small signals should be routed to the EMCCD and VOUT3. The routing of pixels is controlled by the timing on H2SW2 and H2SW3. The optimum signal threshold for that transition between VOUT2 and VOUT3 is when the signal to noise ratio (S/N) of VOUT2 is equal to the S/N of VOUT3. This signal is given by

$$S = \sigma_T^2 \cdot \frac{G + 1}{G} \tag{eq. 1}$$

where G is the EMCCD gain, S is the signal level, and  $\sigma_T$  is the total system noise on VOUT2 in the dark. For values of G greater than 10, the optimum signal threshold occurs when then signal equals the square of the total system noise floor  $\sigma_T$ . Depending on the skill of the camera designer,  $\sigma_T$  will range from 8 to 12 e<sup>-</sup>. If the camera has a total system noise of 10 e<sup>-</sup>, then the threshold should be set to 100 e<sup>-</sup>. However, the floating gate amplifier noise is approximately 60 e<sup>-</sup>, and so would dominate, making it preferable to set the threshold

to at least 3 times the floating gate amplifier noise, or 180 e<sup>-</sup>. Sending signals larger than 180 e<sup>-</sup> into the EMCCD will produce images with lower S/N than if they were read out of the normal floating diffusion output of VOUT2. See Application Note AND9244.

**Temperature Diode**

There is a diode integrated on the same silicon die as the image sensor that can be used to assist temperature regulation. It is not accurate enough to provide a calibrated temperature value, but it can be used to maintain a constant temperature.

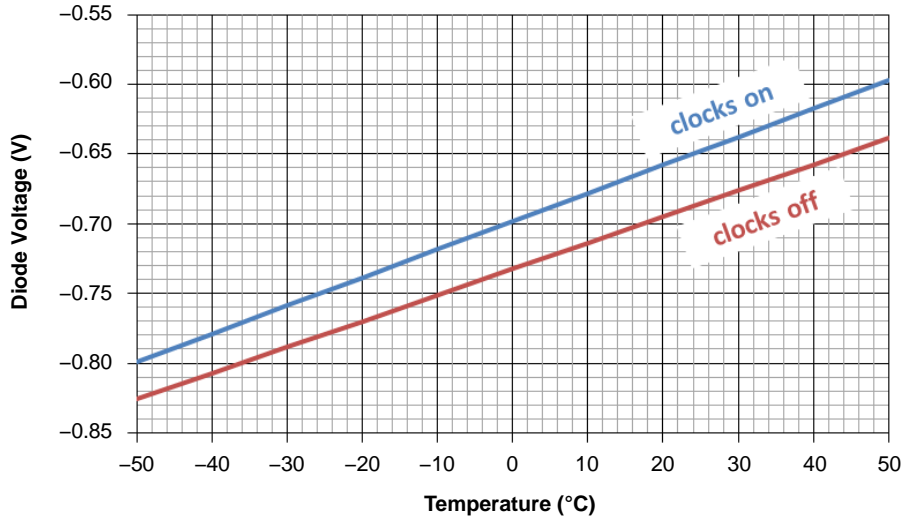
The temperature is sensed by forward biasing the diode with 50  $\mu$ A of current and measuring the resulting voltage drop. The current value most preferred is 50  $\mu$ A. It is recommended that it not be less than 40  $\mu$ A or more than 60  $\mu$ A.

The primary source of inaccuracy in temperature measurement is noise contributed by other clock inputs to the image sensor. The small amount of coupling of the other clocks to the temperature diode is rectified by the temperature diode and causes an offset error in the voltage reading. The magnitude of the offset error is dependent upon factors such as the number of outputs used, and the layout of the camera circuit board. While the error frustrates obtaining

an accurate absolute temperature value, it is expected to be constant and allow the diode to be used for maintaining a constant temperature.

Figure 30 shows the forward biased voltage drop across the diode vs. temperature with a current of 50  $\mu\text{A}$ . There are

two curves showing the offset error. One curve shows the temperature dependence with all image sensor clocks stopped, and the second with all clocks operating at 20 MHz. The offset between the clocks-on and clocks-off curves will be different for every camera design.

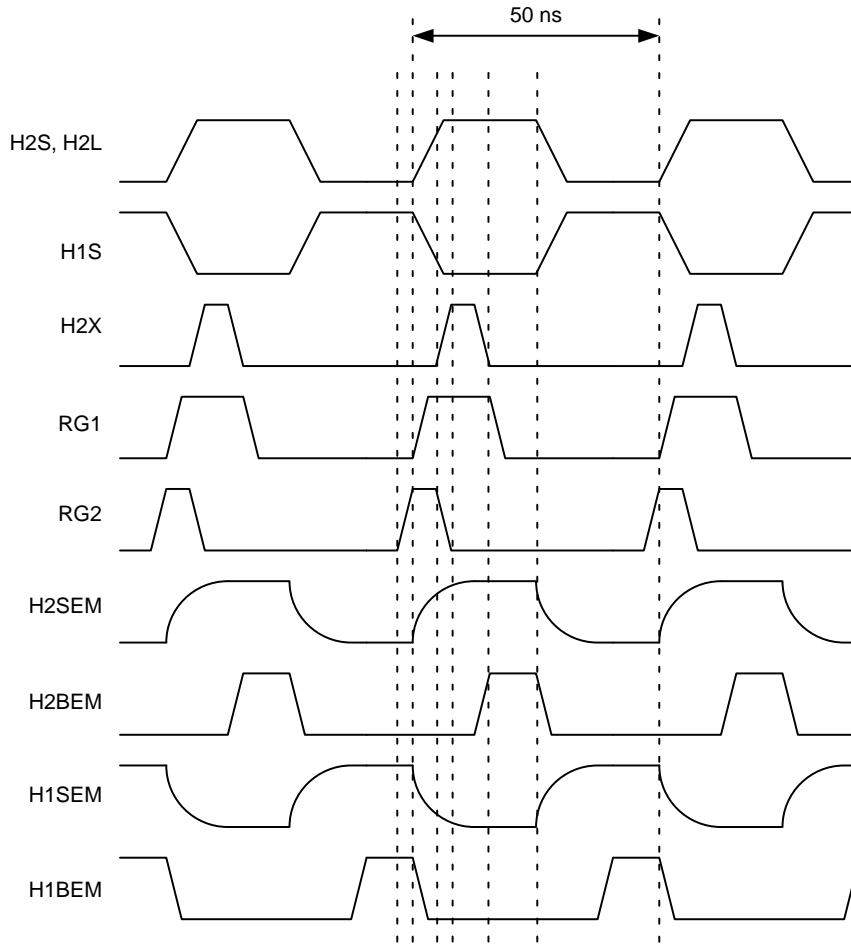


NOTE: The "clocks on" voltage curve will vary significantly from one camera design to the next.

Figure 30. Voltage Drop across Temperature Sensing Diode with Current of 50  $\mu\text{A}$

TIMING DIAGRAMS

Pixel Timing



NOTE: The minimum time for one pixel is 50 ns.

Figure 31. Pixel Timing Pattern P1

**Black Clamp, VOUT1, VOUT2, and VOUT3 Alignment at Line Start**

The black level clamp should start 3 clock cycles into the line and be active for 28 clock cycles of each row. The first photoactive pixel will arrive at the VOUT1 (floating gate) output after 34 clock cycles. The first photoactive pixel will arrive at either the VOUT2 or VOUT3 after 68 clock cycles, depending on the timing of H2SW2 and H2SW3.

When in dual or quad output mode, each row must have exactly 1,036 HCCD clock cycles. The pixels arrive at

VOUT3 on the same clock cycle and exactly two rows after they would have arrived at VOUT2. Changing the number of HCCD clock cycles will introduce an offset between when pixels arrive at VOUT2 or VOUT3.

When in single mode, each row must have exactly 2,072 HCCD clock cycles. The pixels arrive at VOUT3 on the same clock cycle and exactly one row after they would have arrived at VOUT2. Changing the number of HCCD clock cycles will introduce an offset between when pixels arrive at VOUT2 or VOUT3.

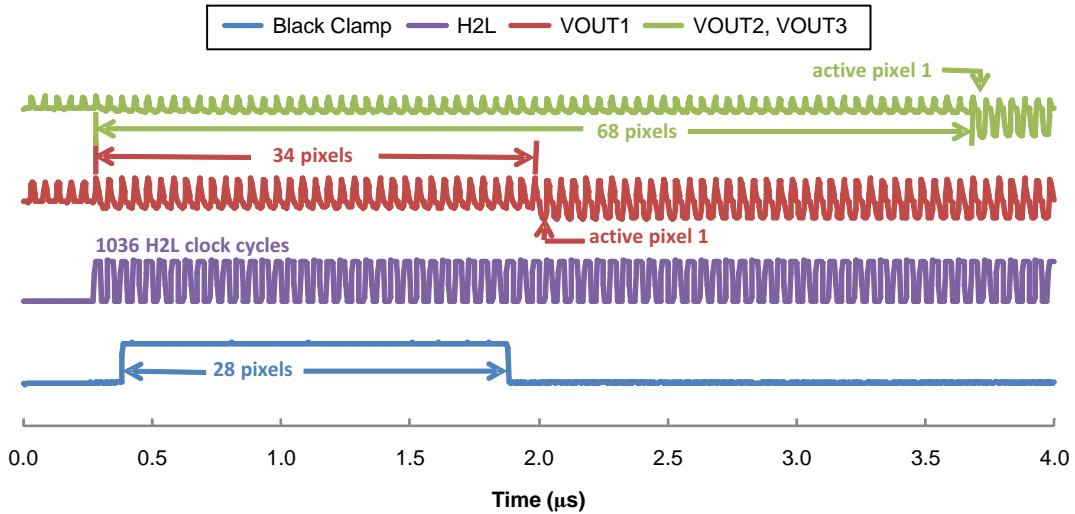


Figure 32. Video Output at Each Line Start

**H2L, VOUT1, VOUT2, and VOUT3 Alignment at End of Line**

The last active pixel (the center column of the image), arrives at VOUT2 or VOUT3 on the 1,036<sup>th</sup> clock cycle of the HCCD. The last photoactive pixel arrives at VOUT1 34 clock cycles before VOUT2 or VOUT3. When in single

output mode, the pixels arrive at VOUT3 one line delayed from when they would have arrived at VOUT2. When in dual or quad output modes, the pixels arrive at VOUT3 two lines delayed from when they would have arrived at VOUT2.

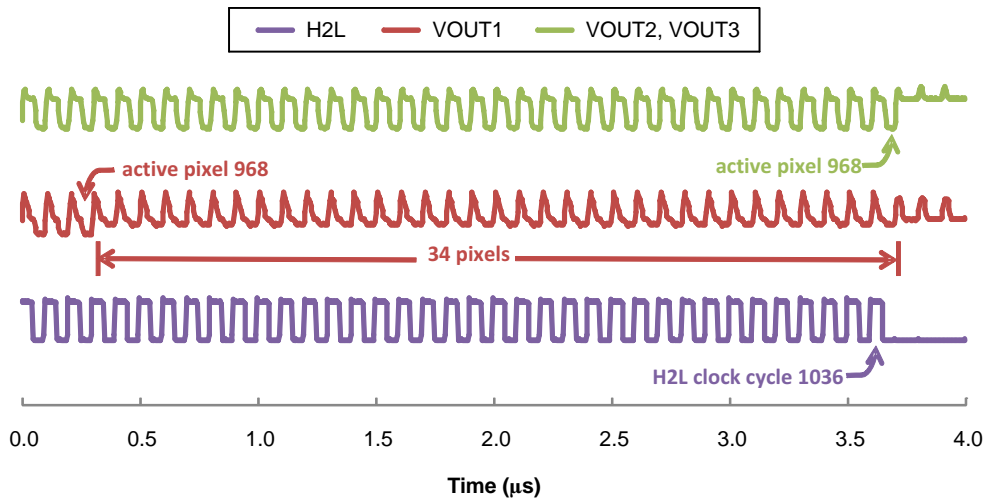


Figure 33. Video Output at End of Each Line for Dual or Quad Output Modes

VCCD Timing

Table 15. TIMING DEFINITIONS

Symbol	Note	Minimum	Nominal	Maximum	Units
$t_{VA}$	VCCD Transfer Time A	0.46	0.50	0.50	$\mu\text{s}$
$t_{VB}$	VCCD Transfer Time B	0.46	1.30	7.50	$\mu\text{s}$
$t_{SUB}$	Electronic Shutter Pulse	1.0	1.5	10.0	$\mu\text{s}$
$t_3$	Photodiode to VCCD Transfer Time	1.0	1.5	5.0	$\mu\text{s}$

V1, V2, V3, V4 Alignment

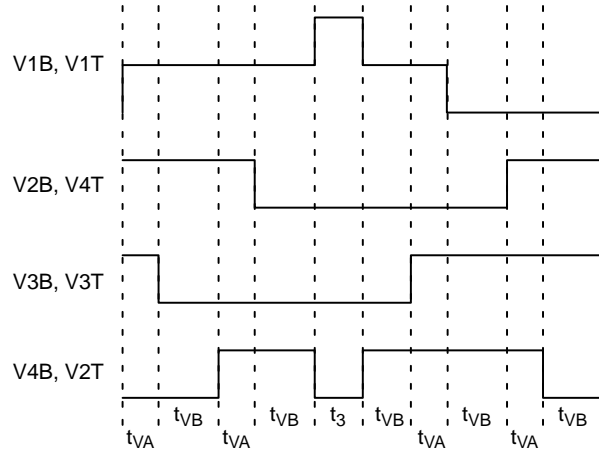


Figure 34. Timing Pattern F1. VCCD Frame Timing to Transfer Charge from Photodiodes to the VCCD when Using the Bottom HCCD, Outputs A or B

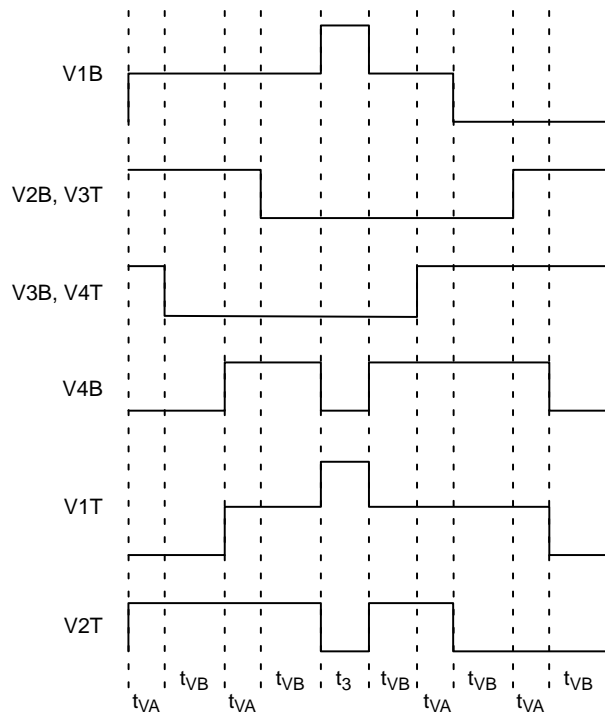
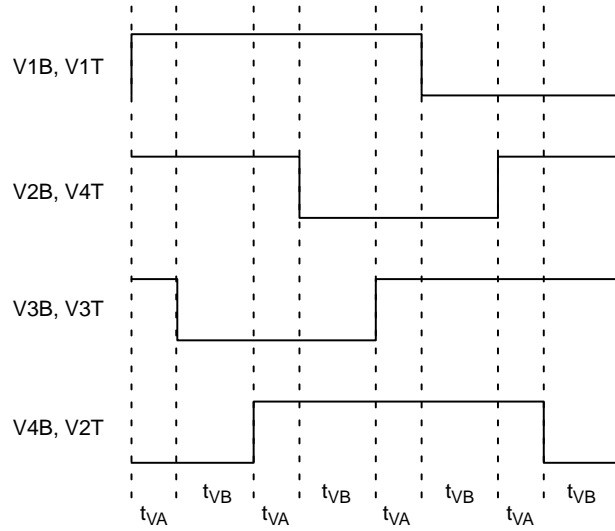
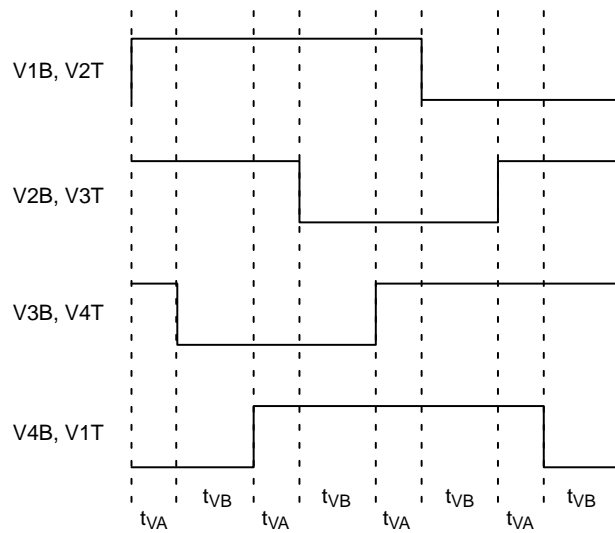


Figure 35. Timing Pattern F2. VCCD Frame Timing to Transfer Charge from Photodiodes to the VCCD when Using All Four Outputs in Quad Mode



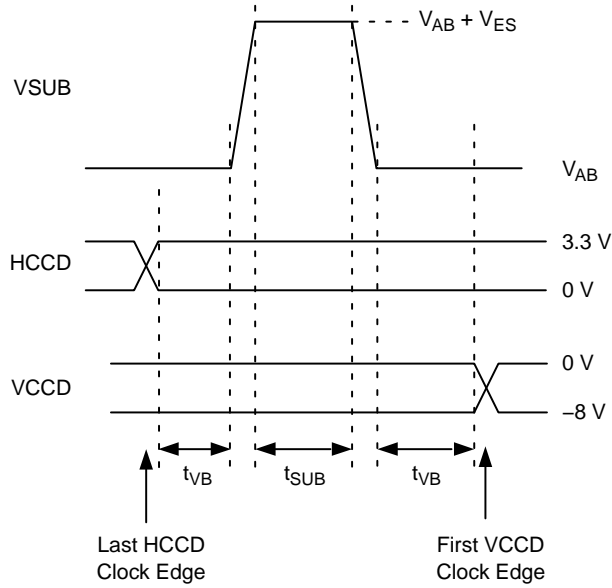


**Figure 36. Line Timing L1. VCCD Line Timing to Transfer One Line of Charge from VCCD to the HCCD when Using the Bottom HCCD, Outputs A or B in Single or Dual Output Modes**



**Figure 37. Line Timing L2. VCCD Line Timing to Transfer One Line of Charge from VCCD to the HCCD when Using All Four Outputs in Quad Mode**

Electronic Shutter



**CAUTION:** Do not clock the EMCCD register while the electronic shutter pulse is high.

**Figure 38. Electronic Shutter Timing Pattern S1**

Clock	State
H1S	High
H2S	Low
H2SW	Low
H2L	Low
H2X	Low
H1SEM	High
H1BEM	High
H2SEM	Low
H2BEM	Low

**Figure 39. The State of the HCCD and EMCCD Clocks during the Frame, Line, and Electronic Shutter Timing Sequences**

**HCCD Timing**

To reverse the direction of charge transfer in a Horizontal CCD, exchange the timing pattern of the H1B and H2B inputs of that HCCD. If a HCCD is not used, hold all of its gates at the high level.

When operating in single or dual output modes, the VDD23cd, VDD1c, and VDD1d amplifiers must still be powered. The outputs VOUT1, VOUT2, and VOUT3 for quadrants c and d may be left unloaded.

**Table 16. HCCD TIMING**

Mode	HCCD a, b Timing	HCCD c, d Timing
Single	H1Ba = H2Bb = H1Sa = H1Sb H2Ba = H1Bb = H2Sa = H2Sb	3.3 V
Dual	H1Ba = H1Bb = H1Sa = H1Sb H2Ba = H2Bb = H2Sa = H2Sb	3.3 V
Quad	H1Ba = H1Bb = H1Sa = H1Sb H2Ba = H2Bb = H2Sa = H2Sb	H1Bc = H1Bd = H1Sc = H1Sd H2Bc = H2Bd = H2Sc = H2Sd

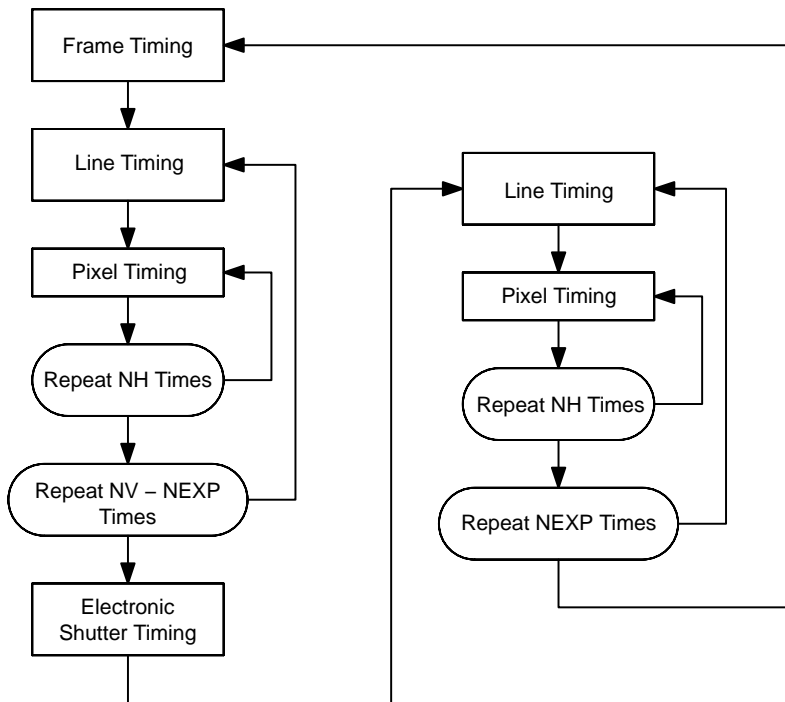
**Image Exposure and Readout**

The flowchart for image exposure and readout is shown in Figure 40. The electronic shutter timing may be omitted to

obtain an exposure time equal to the image read out time. NEXP is the number of lines exposure time and NV is the number of VCCD clock cycles (row transfers).

**Table 17. IMAGE EXPOSURE AND READOUT**

Mode	NH	NV	Line Timing	Frame Timing	Pixel Timing
Single	2,072	1,124	L1	F1	P1
Dual	1,036	562	L1	F1	P1
Quad	1,036	562	L2	F2	P1



**Figure 40. The Image Readout Timing Flow Chart**

**Long Integrations and Readout**

For extended integrations the output amplifiers need to be powered down. When powered up, the output amplifiers emit near infrared light that is sensed by the photodiodes. It will begin to be visible in images of 30 second integrations or longer.

To power down the output amplifiers set VDD1 and VSS1 to 0 V, and VDD23 to +5 V. Do not set VDD23 to 0 V during the integration of an image. During the time the VDD2 supply is reduced to +5 V the substrate voltage reference

output SUBV will be invalid. For cameras with long integration times, the value of SUBV will have to be digitized by an ADC and stored at the time when VDD23 is +15 V. The SUB pin voltage would be set by a DAC. The HCCD and EMCCD may be continue to clock during integration. If they are stopped during integration then the EMCCD should be re-started at +7 V to flush out any undesired signal before increasing the voltage to charge multiplying levels.

The timing flow chart for long integration time is shown in Figure 41.

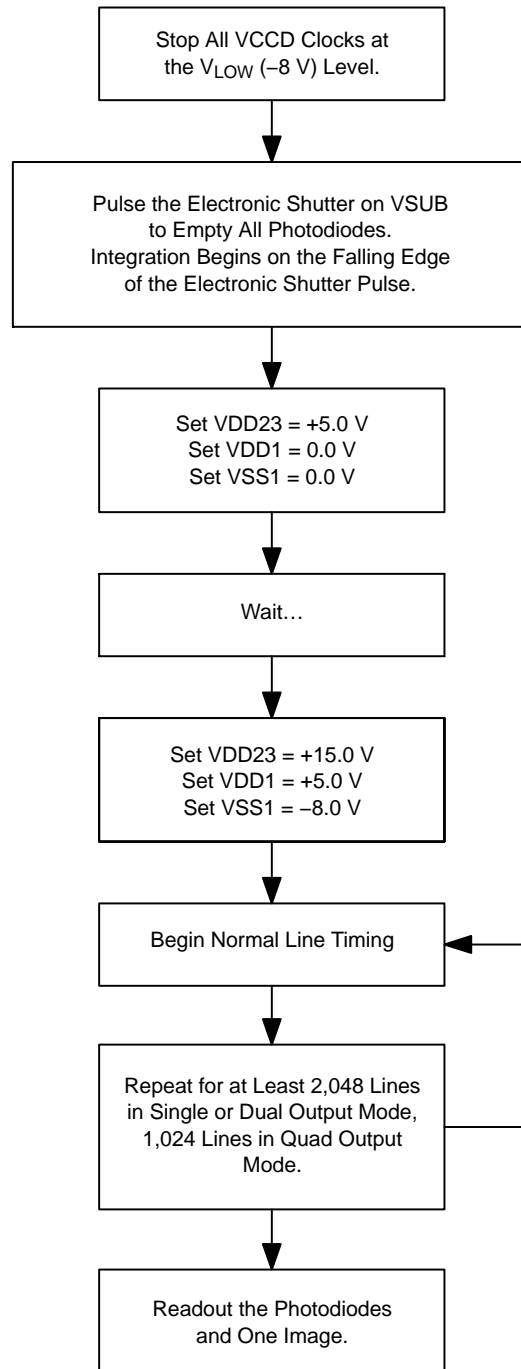


Figure 41. Timing Flow Chart for Long Integration Time

## STORAGE AND HANDLING

Table 18. STORAGE CONDITIONS

Description	Symbol	Minimum	Maximum	Units	Notes
Storage Temperature	T <sub>ST</sub>	-55	80	°C	1
Humidity	RH	5	90	%	2

1. Long-term storage toward the maximum temperature will accelerate color filter degradation.
2. T = 25°C. Excessive humidity will degrade Mean Time to Failure (MTTF).

For information on ESD and cover glass care and cleanliness, please download the *Image Sensor Handling and Best Practices* Application Note (AN52561/D) from [www.onsemi.com](http://www.onsemi.com).

For information on environmental exposure, please download the *Using Interline CCD Image Sensors in High Intensity Lighting Conditions* Application Note (AND9183/D) from [www.onsemi.com](http://www.onsemi.com).

For information on soldering recommendations, please download the *Soldering and Mounting Techniques Reference Manual* (SOLDERRM/D) from [www.onsemi.com](http://www.onsemi.com).

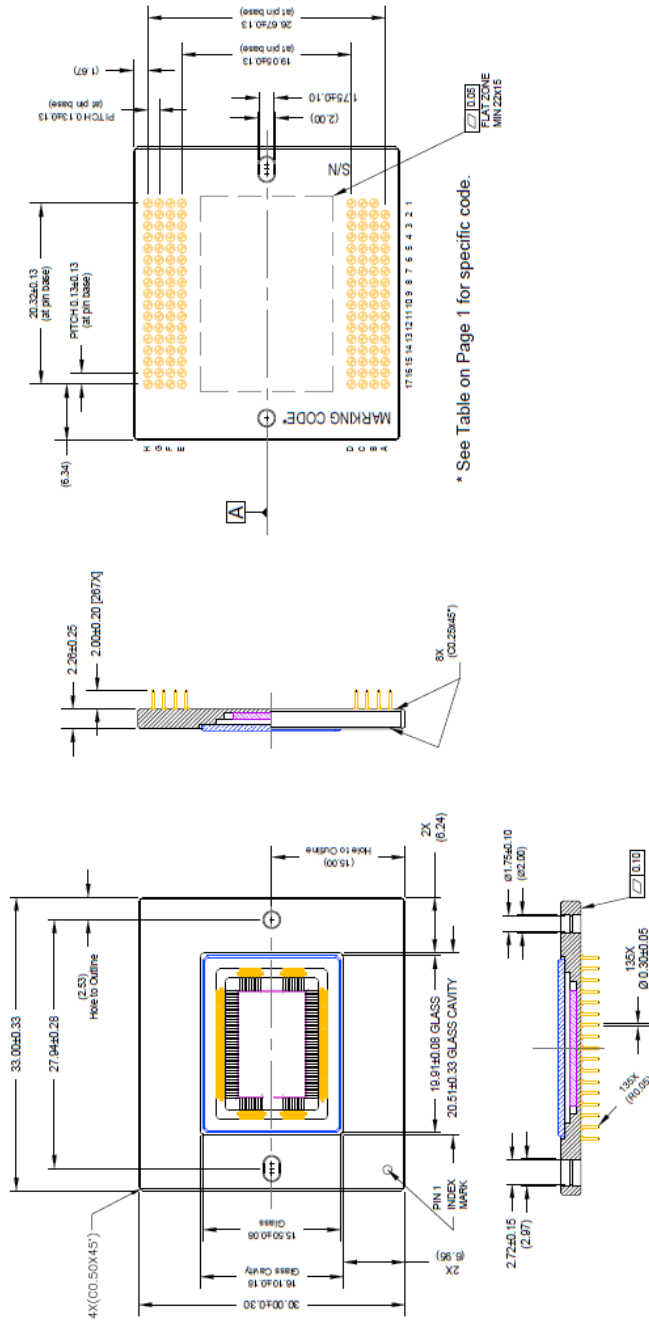
For quality and reliability information, please download the *Quality & Reliability Handbook* (HBD851/D) from [www.onsemi.com](http://www.onsemi.com).

For information on device numbering and ordering codes, please download the *Device Nomenclature* technical note (TND310/D) from [www.onsemi.com](http://www.onsemi.com).

For information on Standard terms and Conditions of Sale, please download [Terms and Conditions](http://www.onsemi.com) from [www.onsemi.com](http://www.onsemi.com).

MECHANICAL INFORMATION

PGA Completed Assembly



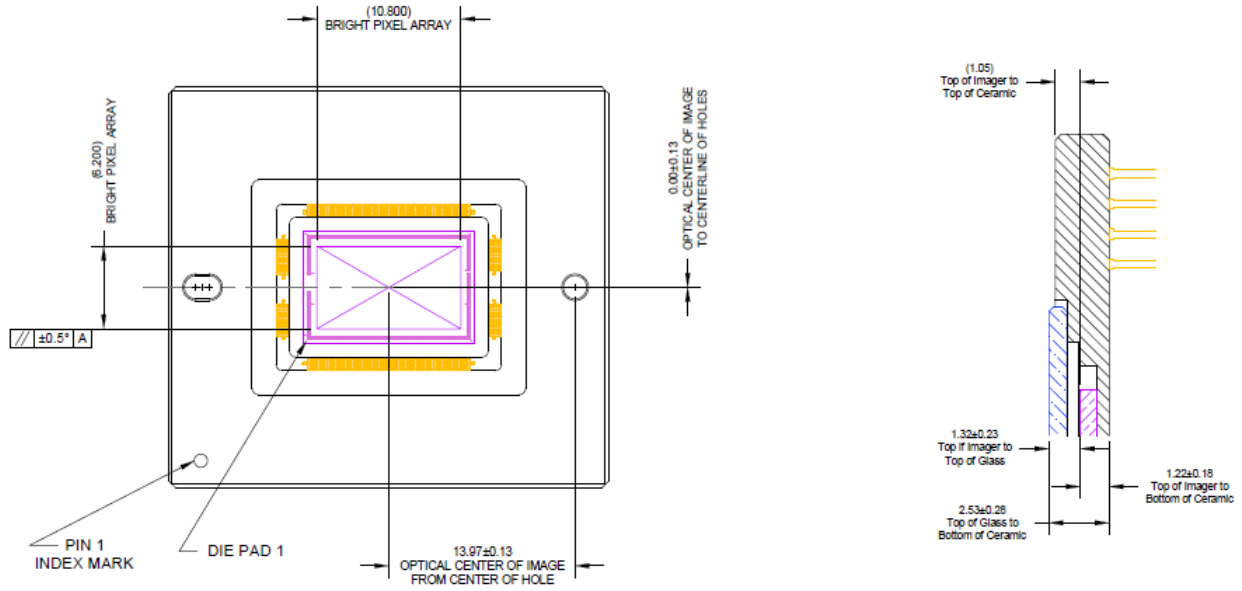
\* See Table on Page 1 for specific code.

Notes:

1. Substrate is a 141-pin ceramic PGA package.
2. Body is black alumina.
3. Pins are Kovar or equivalent, plated with 1.00 microns of gold over 2.00 microns of nickel.
4. Wire is wedge bonded aluminum (1% Si).
5. Ablebond 967-1 epoxy for die attach.
6. No materials to obstruct the clearance through the package holes.
7. Exposed metal is 1.00 micron minimum gold over 2.00 micron minimum nickel.
8. Glass lid is Schott E263Teco, n<sub>D</sub> 1.5231. Thickness 0.76 ± 0.05 mm.
9. Recommended mounting screws: 1.6 × 0.35 mm (ISO standard), 0-80 (unified fine thread standard).

Figure 42. Completed Assembly (1/2)

DIE PLACEMENT



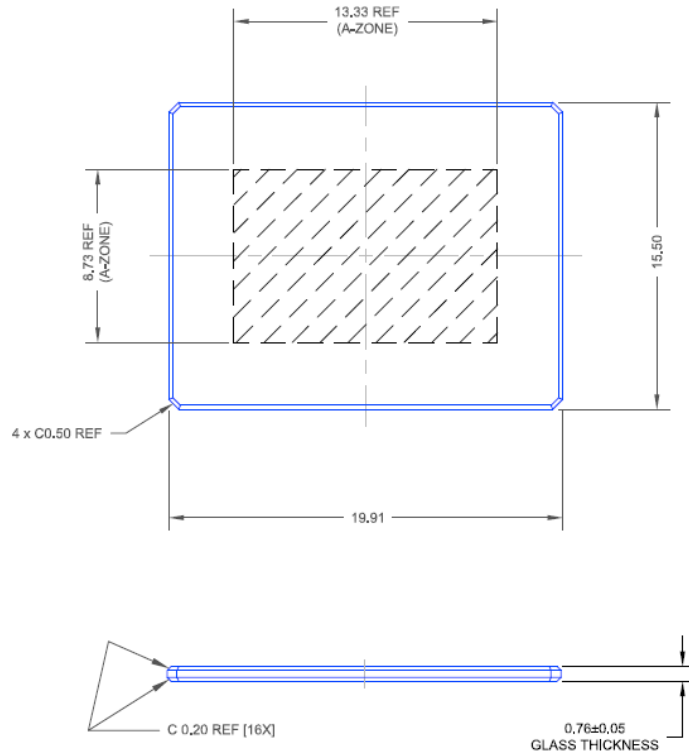
Notes:

1. Die is standard thickness for 150 mm silicon wafer:  $0.675 \pm 0.020$  mm.
2. Singulated die is approximately  $12.910 \times 8.500$  mm, for a 50 micron saw kerf.
3. The optical center of the image area is at the center of the die and the center of the package.

Figure 43. Completed Assembly (2/2)

# KAE-02150


## PGA Clear Cover Glass



### Notes:

1. Dust and Scratch: 10 micron maximum ("A" zone)
2. Glass Material: Schott D263T eco

**Figure 44. PGA Clear Cover Glass**

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